EGGBOT

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The Pursuit of the Perfect Egg

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> Dominic Doty *Boulder Colorado, May 5 2019*

A final project for the Embedded System Design course at the University of Colorado, Boulder. The Eggbot is a single axis robot with a temperature controlled water bath created for the goal of cooking the perfect soft boiled egg. The bot also serves a secondary purpose of precision tea brewing, and a tertiary purpose of heating water to specific temperatures.

The stated course goal of the project was to explore an area of interest while implementing new hardware and software. My personal goal extends beyond this, to create a consumer quality product that can be used every day in my home, while also showcasing the development board created through the duration of this course.

Figure 0.1: Concept Sketch of the EggBot.

LIST OF TABLES

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LISTINGS

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A C R ON Y M S

- ADC Analog to Digital Converter
- AT⁴² Capacitive Touch Sensor AT42QT110
- AT89 80C52 Microcontroller AT89C51RC2
- BCD Binary Coded Decimal
- COTS commercial off the shelf
- DIP Dual Inline Package
- DRV Stepper Driver DRV8825
- ESD Embedded System Design
- ISR Interrupt Service Routine
- LCD Liquid Crystal Display
- mA milliamperes
- MCAD Mechanical Computer Aided Design
- PCB Printed Circuit Board
- QFN Quad Flat No-lead
- SPI Serial Peripheral Interface
- UART Universal Asynchronous Receiver and Transmitter
- VAC Volts Alternating Current

This chapter covers the design of the Eggbot with specific information about each subsystem of the bot including electrical, firmware, and mechanical design. Design trade-offs, component selection, and design intent are covered. As previously mentioned, my principal goal in the creation of the Eggbot was to achieve a polished, consumer quality result that could showcase the board I spent the semester creating.

1.1 HARDWARE DESIGN

1.1.1 *System Overview*

The electrical aspects of the project can be classified into three main categories: thermal control, motion control, and user interface. Thermal control consists of a commercial off the shelf ([COTS](#page-6-1)) kettle, connected to 120 Volts Alternating Current ([VAC](#page-7-0)) by a relay. Motion control is made up of a stepper motor and a Stepper Driver [DRV](#page-6-2)8825 (DRV) based driver board. User interface includes a capacitive touch keypad, based on the Capacitive Touch Sensor AT42QT110 ([AT](#page-6-3)42), and a Liquid Crystal Display ([LCD](#page-6-4)), implemented in previous labs. The center of the electrical system is the 80C52 Microcontroller AT89C51RC2 ([AT](#page-6-5)89) microcontroller board. The microcontroller will not be covered in detail in this report, since it is the standard board built in the Embedded System Design ([ESD](#page-6-6)) course. The system block diagram is shown in Figure [1](#page-8-3).1.

Figure 1.1: System Hardware Block Diagram.

1.1.2 *Relay*

The relay selected is an RZF1-1A4-Loo5 from TE Connectivity $(D.1)$ $(D.1)$. This relay was selected because it features blade terminals for the [VAC](#page-7-0) connected side of the relay, and through hole pins for the coil side of the relay. This eases connection of the relay to thick gauge, high voltage wire. It also provides some physical isolation between the low voltage control pins and the high voltage terminals. This increases system safety since high voltages need not be broken out on the same Printed Circuit Board ([PCB](#page-6-7)) as low voltage signals.

Figure 1.2: Relay Driver Circuit.

The relay is driven by a transistor from the microcontroller as shown in Figure [1](#page-9-1).2. The relay was added here to utilize the partially implemented circuitry, and to take advantage of the LED as an indicator of power being supplied to the relay. The transistor base is driven by two pull-up resistors because the original pull-up resistor was sized to light the LED included in the circuit. With the addition of the relay, the pull-up resistor needed to be resized to supply adequate current to the transistor, and it was more efficient to add a parallel resistor than to remove the original one. The pull-up is sized to supply 10 milliamperes (mA) (mA) (mA) to the base of the transistor, enough to fully turn on the transistor with the LED current of 6[mA](#page-6-8) and a coil current of 12[mA](#page-6-8).

This is admittedly somewhat aggressive since the maximum sink current for one microcontroller pin is 10[mA](#page-6-8), but I deemed it necessary to drive the transistor as hard as possible since the coil is an inductive load and will present much higher currents at turn on. To eliminate the inductive kick from the relay coil, a 1N4007-TPMSCT-ND diode was connected across the relay coil as a snubber diode as shown in Figure [1](#page-10-1).3.

Figure 1.3: Relay connection itself.

1.1.3 *Temperature Sensing*

Temperature sensing is provided by a 10K thermistor (unknown brand), analog filtering circuitry, and a MCP3002-I/P Analog to Digital Converter ([ADC](#page-6-9)) from Microchip Technology [\(D.](#page-103-0)2).

The thermistor is linearized by using it as one leg of a resistor divider (figure 1.5 1.5). The linearizing resistor was selected using Figure 1.4 as a reference. In this figure, it can be seen that a resistor value of 2.7 $k\Omega$ ¹ would yield a mostly linear reading from 20° C to 90° C. Since this is the region of interest for cooking with water just under boiling, this linear range works well².

After linearization, the sense voltage is buffered with a MCP602-I/P operational amplifier from Microchip Technology $(D.5)$ $(D.5)$. This allows the sense voltage to be sampled with a high impedance input, and driven to a low impedance output. This is essential for driving the low-pass filter and [ADC](#page-6-9) that follow. This amplifier in particular was selected because it is a rail-to-rail amplifier, capable of driving its output voltage very near to both ground and V+ supply.

The low-pass filter was sized starting with the capacitor on hand, a 47uF electrolytic. A cutoff frequency target was set at 40Hz to attempt to attenuate AC noise from the kettle at 60Hz. With this target, a resistance of 82 Ω was selected, yielding a cutoff frequency of 41.3Hz.

While the capacitor value chosen for the filter may seem like overkill, it also helps with the sampling of the [ADC](#page-6-9). The [ADC](#page-6-9) uses a sample and

¹ R₂₅ is the resistance at 25[°]C, in this case 10 k Ω

² Recall that the boiling point in Boulder, Colorado is approximately 95°C

Figure 1.4: Thermistor linearity in a resistor divider for multiple resistor divider values. *Thermistor signal conditioning: Dos and Don'ts, Tips and Tricks* – <https://www.embeddedrelated.com/showarticle/91.php>

hold front end which appears as a small capacitor being rapidly connected and disconnected from the line. The sampled voltage must have a low impedance source so the [ADC](#page-6-9) sampling does not significantly affect the sampled voltage. The combination of the op amp buffer and large capacitance effectively drive the [ADC](#page-6-9) input.

Figure 1.5: Thermistor linearization, filtering, and [ADC](#page-6-9) schematic.

The specific [ADC](#page-6-9) was selected for its Serial Peripheral Interface ([SPI](#page-6-10)), low cost, Dual Inline Package ([DIP](#page-6-11)) form factor, and 10-bit resolution. The [SPI](#page-6-10) interface was preferable because the [AT](#page-6-5)89 includes a hardware [SPI](#page-6-10) peripheral. While the [AT](#page-6-5)89 also has a hardware Universal Asynchronous Receiver and Transmitter ([UART](#page-7-1)), this is used for system programming and debugging.

1.1.4 *Stepper Driver*

The stepper motor and its driver were components that I had on hand at the beginning of the project, so their selection was not subjected to much scrutiny. The DRV8825³ is a common chip available cheaply on small breakout boards. The breakout board includes a current limiting potentiometer and some decoupling capacitors.

1.1.5 *End-stop*

For the end-stop, a microswitch D2FS-FL-N from Omron was selected $(D.4)$ $(D.4)$. The end-stop was selected for its low cost and high durability. It is interesting to note standards of durability and usage are very different depending on the engineer's perspective. This switch is billed as "Developed for a few number of operations [sic] during a long period of use"⁴ , which for an industrial context translates to a minimum lifetime of 10,000 operations. Needless to say, 10,000 operations far exceeds the expected lifetime of my system.

Since the end-stop is being connected directly to an interrupt pin on the processor, it requires further processing before connection. Enter the debouncing and triggering schematic shown in Figure [1](#page-12-2).6.

Figure 1.6: End-stop debouncing and triggering circuit.

³ <https://www.pololu.com/product/2133>

The left side of the schematic forms the debouncing circuit, with R12 acting as a pull-up, and R13 and C17 forming a low-pass filter⁵. U12 is another MCP602 operational amplifier $(D.5)$ $(D.5)$ acting as a buffer to provide a low impedance source to the next part of the circuit.

The right side of the schematic forms a Schmitt Trigger. With the chosen values of resistors⁶, the trigger should provide hysteresis switch values of $1.875V$ and $3.125V$. This prevents the ENDSTOP output from lingering in the digital logic grey area, eliminating spurious pulses during the transition between 0 and 1.

1.1.6 *Capacitive Touch*

Capacitive touch was selected as the interface for the system since it allows the buttons to be completely enclosed, preventing water ingression into the system. Since the primary objective of the system involves pots of water, this seemed prudent. The capacitive touch interface is based on the AT_{42} AT_{42} by Microchip Technology [\(D.](#page-138-0)3).

During part selection, the user interface was not yet fixed. This chip was selected primarily because it supported up to 11 key inputs, which provided a healthy margin for interface design. Another key consideration was the [SPI](#page-6-10) interface provided on this chip. This allowed the sharing of the communications bus with the [ADC](#page-6-9) with only one additional pin used as a chip select signal. This proved key as the final system design used every pin available on the [AT](#page-6-5)89. The breakout board schematic is shown in Figure [1](#page-14-2).7.

Normally the passive component values would be tested and adjusted with the electrodes designed for the system, but due to time constraints this was not possible. Values were chosen in the middle of the suggested range in the datasheet (D_3) , with the option to modify the electrode design later if required.

Since the part is only available in a Quad Flat No-lead ([QFN](#page-6-12)) package⁷, it was necessary to make a breakout board for the device, Figure [1](#page-14-3).8. The board provides decoupling capacitors along with all necessary supporting passive components. All passive components are 0603 package, which allowed the board be miniaturized to just under 1.25" square.

⁵ Selected with reference to <http://www.ganssle.com/debouncing.htm>

⁶ Selected with reference to *The Art of Electronics* by Horowitz and Hill

⁷ There are no [DIP](#page-6-11) capacitive touch chips that are not prohibitively expensive

Figure 1.7: [AT](#page-6-3)⁴² Capacitive Touch Breakout Schematic.

Figure 1.8: [AT](#page-6-3)⁴² Capacitive Touch Breakout [PCB](#page-6-7).

1.2 firmware design

1.2.1 *System Overview*

The firmware design is centered around the USER INTERFACE STATE machine and accompanying program state variable. The user INTERFACE STATE MACHINE controls the entire system, storing the current state in a globally accessible variable. Each sub-task is then able

to get the expected state from the PROGRAM STATE VARIABLE and act accordingly. The remaining structure is shown in Figure [1](#page-15-1).9.

Figure 1.9: System Software Block Diagram.

Just over 1800 entirely new lines⁸ of code were written for this project. Each section below contains the count of new lines in that code module, but note that these were compiled by hand and may contain minor inaccuracies.

Using the Linux command line⁹, the total number of lines in the project was determined to be just over 3200 lines of code (including code reused from previous projects).

1.2.2 *Scheduling Timer*

All tasks, including the USER INTERFACE STATE MACHINE are scheduled by a timer. The timer runs continuously and dispatches each of the other tasks at set interval. This allows some tasks to be run at a higher frequency than others in the style of a cyclic executive.

The timer runs on a 5ms interval, and can dispatch tasks at 5ms, 10ms, 20ms, 40ms, and 80ms intervals. The tasks are scheduled at the following intervals:

- 5ms step generator
- 10ms BUTTON TASK
- 20ms thermal control task, timer task
- 40ms user interface state machine
- 80ms DISPLAY TASK

180 new lines of code were written for this module.

⁸ Code not previously used in any other project

⁹ *find . -name '*' | xargs wc -l*

1.2.3 *User Interface State Machine*

The USER INTERFACE STATE MACHINE makes up the core logic of the system. It takes user input from the BUTTON TASK and monitors all the other tasks to determine the current and future state of the system. The state machine diagram is shown in Figure 1.[10](#page-16-1).

Figure 1.10: User Interface State Machine Diagram.

The USER INTERFACE STATE MACHINE interacts with the other tasks through the PROGRAM STATE VARIABLE, which takes the form of a struct that stores the state of the system including:

- Current temperature
- Goal temperature
- Temperature control enabled
- Current time
- Goal time
- Timer run enabled
- Preset name
- Current UI state
- Last UI mode
- Ring buffer of button events
- Preset updated flag

The first set of items are self explanatory for temperature and timekeeping. The second half bear a more detailed explanation. The *preset name* stores the name of the currently loaded preset¹⁰ for display by the LCD. The *last UI mode* stores the last mode the UI was in, so it can return to the same mode on completion or cancellation of the current cooking run. The *ring buffer* holds button events from the BUTTON TASK that have not yet been processed. The *preset updated flag* is used to alert the LCD when the user has selected a different preset. This allows the LCD to store minimal state, but also avoid updating the display more than necessary.

The USER INTERFACE STATE MACHINE can also trigger actions by the stepper motor using the stepper command interface to command the stepper motor to home itself or move the motor to a specific position. It should be noted that when the system goes into a sleep mode, the stepper position is no longer guaranteed, and as such the user interface state machine forces the stepper to be homed before any other tasks can execute.

278 new lines of code were written for this module.

1.2.4 *Display Task & LCD Driver*

The DISPLAY TASK maintains the [LCD](#page-6-4) output to the user. In all states except sleep, it maintains an up to date temperature output. When flagged by the USER INTERFACE STATE MACHINE that the user preset has been updated, the $DISPLAY$ TASK updates the [LCD](#page-6-4) to the new preset name, target temperature, and target time. The DISPLAY TASK also monitors the state of the system timer, and when enabled, updates the current time output on the [LCD](#page-6-4).

The DISPLAY TASK sits atop the LCD DRIVER, which was written for a previous lab assignment in [ESD](#page-6-6).

157 new lines of code were written for this module.

1.2.5 *Step Generator & Output Routine*

The stepper motor driver is made up of three main parts: stepper command interface, step generator, and step output service routine. The stepper driver was written with the intention to make it capable of full trapezoidal motion planning 11 for arbitrary movements.

¹⁰ Egg presets include very hard, hard, medium, and soft

¹¹ For more information on the trapezoidal motion profile see: [https://www.pmdcorp.com/](https://www.pmdcorp.com/resources/get/mathematics-of-motion-control-profiles-article) [resources/get/mathematics-of-motion-control-profiles-article](https://www.pmdcorp.com/resources/get/mathematics-of-motion-control-profiles-article)

The STEP GENERATOR is the core and most complex part of the stepper driver. The step generator takes commands from two ring buffers that specify a target position and velocity. Using these targets, it calculates step timings to accelerate from the current velocity to the target velocity. Once the target velocity is achieved, the STEP GENERATOR will maintain that velocity until the target position is achieved. Pulses are placed into a double buffer shared with the STEP OUTPUT SERVICE ROUTINE for execution.

The step generator also generates special control codes which are injected into the stream of step times to control the direction of the stepper motor. This is required since direction changes must be synchronized at specific points in the step pulse stream.

This driver did not achieve a fully generalized state however, since the user must command the step generator with an accelerating move and then a decelerating move. This simplifies the generator by lifting the requirement that the generator "look ahead" to determine when deceleration is required to start. Because the system only performs one specific, repeated motion, this reduction in complexity was acceptable.

Acceleration is implemented in a novel way to optimize the step generation process. Rather than use standard acceleration in $\frac{mm}{s^2}$, the system instead divides or multiplies the time in between steps by two during acceleration and deceleration respectively. In practice, this produces an exponential velocity curve which is actually smoother than a trapezoidal profile. This comes with the added benefit that acceleration calculations can now be greatly simplified by using bit shifts instead of multiplication and division.

The STEP OUTPUT SERVICE ROUTINE is where the pulses meet the motor so to speak. The routine uses a timer and the values provided by the STEP GENERATOR to execute step pulses at precision intervals, moving the motor. As previously mentioned, the routine also changes the direction of the motor on receipt of specific codes in the time stream. The use of double buffers allows the step timing to be generated asynchronously while the service routine executes them on precision intervals.

The final part of the stepper driver, the STEPPER COMMAND INTERface, provides a wrapped interface to add movement commands to the two ring buffers that serve as the input to the STEP GENERATOR.

562 new lines of code were written for this module.

1.2.6 *Button Task & Capacitive Touch Driver*

The BUTTON TASK periodically polls the state of the capacitive touch buttons and recognizes both short and long presses of the buttons. When a button event is registered, the BUTTON TASK then buffers it in the button event ring buffer for the user interface state machine to handle. Originally long presses were to be used for some other user interface functions like programming custom presets, but the scope of the project proved too great to allow that to be implemented. Long presses are currently ignored by the state machine.

The BUTTON TASK sits on top of the CAPACITIVE TOUCH DRIVER, which provides initialization routines and routines to poll the current state of the AT_{42} AT_{42} , the CAPACITIVE TOUCH DRIVER itself sits atop a [SPI](#page-6-10) driver, which provides routines to complete basic transfers.

201 new lines of code were written for this module, not including 109 for the [SPI](#page-6-10) driver which is shared with the [ADC](#page-6-9) driver.

1.2.7 *Thermal Control & ADC Driver*

The THERMAL CONTROL task performs a modified bang-bang control of the kettle. When THERMAL CONTROL is activated, it calculates an intermediate temperature goal as 25% of the difference between the current temperature and the final goal temperature. The heater is then activated till this intermediate goal is reached, at which point it is disabled. The controller then waits while the kettle temperature overshoots and eventually stabilizes. At this point, the above procedure is repeated with a new intermediate temperature goal.

It can be seen that as the temperature gets nearer to the final goal temperature, the difference between the current temperature and the intermediate goal temperature gets smaller. This translates to shorter periods with the heater engaged, to less overshoot, and to more precise control. This has significantly reduced the overshoot over traditional bangbang control, but there is still room for improvement.

THERMAL CONTROL sits atop the ADC DRIVER, which again utilizes the [SPI](#page-6-10) driver. Similar to the CAPACITIVE TOUCH DRIVER, the ADC driver implements initialization routines and routines to take readings from the [ADC](#page-6-9).

226 new lines of code were written for this module, not including 109 for the [SPI](#page-6-10) driver which is shared with the CAPCAITIVE TOUCH DRIVER.

1.2.8 *Timer Task*

The TIMER TASK is one of the simplest tasks in the system. It simply maintains a Binary Coded Decimal ([BCD](#page-6-13)) timer to be used to track the amount of time since cooking began.

43 new lines of code were written for this module.

1.2.9 *Endstop Interrupt Service Routine*

The ENDSTOP INTERRRUPT SERVICE ROUTINE is triggered when the endstop is pressed. The routine simply updates a flag which the main routine can access, and stops the STEP OUTPUT SERVICE ROUTINE timer. Stopping this timer is done as an extra safety measure, since the timer

should never be running when the endstop is triggered. If the system enters and unforeseen state, this will prevent the motor from driving itself continually into the endstop.

62 new lines of code were written for this module.

1.3 mechanical design

1.3.1 *Design Overview*

Mechanical design is not a focus of the [ESD](#page-6-6) course, but as part of my goal to create a consumer quality project, time was spent on mechanical design. I feel that it should be at least briefly covered here.

The design of the system was undertaken using Onshape, a cloud based Mechanical Computer Aided Design ([MCAD](#page-6-14)) tool. The primary structure of the device is made out of .118" clear acrylic. Acrylic was selected for its low cost, high clarity, and ease of laser cutting, which allows the parts to be fabricated quickly and precisely.

The interior of the base was designed with four partitioned areas. The primary purpose of these partitions was to limit paths for water ingression directly to the system electronics, and as such the opening for the belt and extrusion are in a single partition with no electronics. The secondary purpose of the partitioned areas is limit the mingling of high and low voltage systems. One partition serves this purpose, containing the AC-DC converter and AC relay for controlling the kettle. A render of the complete system is shown in Figure 1.[11](#page-20-2).

Figure 1.11: CAD Render of Eggbot created with Onshape [MCAD](#page-6-14).

The other main component is the aluminum extrusion¹² which is the basis for the linear motion components. The motion platform eschews a traditional linear guide or roller bearings, and instead lets the acrylic carriage slide directly on the extrusion. Because the loading on the carriage is minimal and the accuracy requirement is non-existent, this solution is adequate. The carriage is moved by a GT2 bel $t¹³$ running over a crowned pulley at one end and a 16 tooth cog at the other.

¹² <https://us.misumi-ec.com/>

¹³ <https://sdp-si.com/products/timing-belts/gt2.php>

IMPLEMENTATION & VERIFICATION

This chapter covers implementation and verification of the design outlined in Chapter [1](#page-8-0). This includes details of the actual construction of the system, issues encountered, and tests performed to verify the system functionality. The second section also goes into further detail about how the firmware design was implemented and tested, including code listings.

2.1 hardware implementation & verification

2.1.1 *System Overview*

The system was implemented in small chunks of concurrent design, firmware development, and hardware development. Usually this was limited to one block of the system hardware diagram (Figure [1](#page-8-3).1) at a time. For example, the temperature sampling circuit was broken down into several elements: linearization, buffering, filtering, and [ADC](#page-6-9) conversion. Each of these parts was implemented in hardware and tested before moving onto the next. Finally once the [ADC](#page-6-9) was implemented, a basic firmware driver was implemented to test that portion of the circuit. After the basic driver was implemented, more complex functions are implemented referencing the requirements from the firmware block diagram (Figure [1](#page-15-1).9). Finally these were tested. By using this method, each block in the diagram can be assured error free (mostly, at least) before proceeding to system level integration.

2.1.2 *Relay*

As mentioned in the design section for this module, [1](#page-9-0).1.2, the relay is driven by a simple transistor arrangement with a flyback diode. I first populated the relay and flyback diode alone on a small piece of prototype [PCB](#page-6-7), and made long wire leads for the control inputs. This module was tested using a DC power supply, external to the board. Ideally I would have verified that the flyback diode was indeed clamping the inductive spike, but as my oscilloscope is analog, I did not have a way to capture this.

The module was then connected to the main [PCB](#page-6-7) via a transistor already in place to drive an LED. Testing this revealed that the base driving resistor was not adequate to drive the load of the relay. A new base resistor value was then calculated as detailed in [1](#page-9-0).1.2 and implemented by soldering a second resistor in parallel with the already installed resistor, as

removing the installed resistor was deemed too risky. This configuration worked.

2.1.3 *Temperature Sensing*

The system overview section ([2](#page-22-2).1.1) details the process taken with the temperature conversion circuit, so it will not be repeated here. This section will instead focus on the issues encountered in implementation. Originally, the circuit utilized a [LM](http://www.ti.com/lit/ds/symlink/lm158-n.pdf)358 operational amplifier from Texas Instruments. When tested, the thermistor would produce expected values, but the voltage after the buffering and filtering circuit was not correct. Fortunately I had encountered this issue before, which made it easy to track down. The cause was the fact that the $LM_{35}8$ $LM_{35}8$ is not a rail-to-rail operational amplifier. Since the linearization range drives the thermistor across the majority of the 0-5v range, not using a rail-to-rail amplifier significantly modifies the signal.

After the issue was recognized, the amplifier was replaced with a MCP602 from Microchip $(D.5)$ $(D.5)$. This part swap immediately remedied the issue. I also went ahead and ordered 25 to replace my supply of non rail-to-rail amplifiers, since the price is less painful than tearing my hair out.

The block was also tested with the kettle running on AC power just above it to check for induced noise. This showed very little noise on the line, but unfortunately I do not have an oscilloscope capture of this measurement.

2.1.4 *Stepper Driver*

The DRV8825¹ breakout board was soldered to a small piece of protoboard to allow the input and output pins to be broken out to connectors, and expose the microstepping control pins². This proved a boon since the original design called for the driver to be run in $1/16$ step mode, which was eventually reduced to $1/4$ step mode to reduce the load on the microcontroller. If these configuration pins had been jumpered with solder, this change would have been much more painful.

Limited testing was performed on the module itself since it was purchased complete. I did briefly install the driver in my 3D printer to verify that it was functional.

2.1.5 *Endstop*

The endstop circuit was plagued with the same rail-to-rail amplifier issues detailed in the section on temperature sensing. Fortunately this was

¹ <https://www.pololu.com/product/2133>

² The [DRV](#page-6-2) can drive steppers in full step, 1/2 step, 1/4 step, 1/8 step, and 1/16 step based on the state of these jumper pins

quickly fixed by the same switch to a MCP602 from Microchip $(D.5)$ $(D.5)$. Logic captures were performed to confirm the performance of the debouncer. Since it is directly connected to the processor interrupt pin, it is critical that it does not bounce.

Figure 2.1: Capture showing the raw signal received from the button on top, and the debounced circuit output on the bottom. Captured with a generic Cypress FX2 based logic analyzer and sigrok/PulseView at 24MHz sample rate.

A logic capture of a button cycle is shown in Figure [2](#page-24-1).1. The button is pressed just past 2ms in the capture, and bounces till about 3.5ms. The debounced output goes low at approximately 17ms. While 14ms is a relatively long latency between button press and output signal change, homing speed makes this a non-issue. Homing takes place at 20 mm/s, which means the carriage travels .3 mm (.010") in that latency time, which is not enough to hit the end of the endstop travel.

2.1.6 *Capacitive Touch*

As mentioned in the chapter about capacitive touch hardware design: [Capacitive Touch,](#page-13-0) I designed a small breakout board for the AT_{42} AT_{42} capacitive touch chip from Microchip. My first attempt at designing a breakout used 0805 passives, and the components were fairly spaced out for the clearance I assumed I needed for hand soldering. This board design is shown in Figure [2](#page-24-2).2.

Figure 2.2: Capacitive touch breakout board for AT_{42} AT_{42} , version 1 design. Render created in KiCad EDA.

After printing out this board design at 1:1 scale and comparing it to my soldering iron, I decided that the original space allowance was larger than necessary and that I would also be comfortable attempting to move to smaller passive components, namely 0603's. This was also informed by the fact that I was committing to soldering a QFN32 in the AT_{42} AT_{42} , so moving to smaller passives did increase the total difficulty of the proposition by much.

Figure 2.3: Capacitive touch breakout board for AT_{42} AT_{42} , version 2 design. Render created in KiCad EDA.

Version two of the design, shown in Figure [2](#page-25-0).3 moves to 0603 passives, and much tighter component spacing as mentioned before. This allowed the board to be reduced to near 1.25" square. While this was not required for the design since board space is plentiful on the main [PCB](#page-6-7), it was an interesting exercise nevertheless.

The capacitive touch [PCB](#page-6-7) was ordered from [PCBWay.](https://www.pcbway.com/) The boards arrived about a week after ordering them, in good shape. Due to the pricing model at [PCBWay,](https://www.pcbway.com/) it makes sense to order a minimum quantity of 10. They often make a slightly larger quantity than ordered to offset process yield rates, but will send you the extra quantity if they all pass testing. Due to this, I received 11 boards instead of 10. I continuity tested all the pads of the boards after receipt and found no unexpected shorts or open connections.

I also ordered extra components to allow myself multiple attempts at populating boards. This proved unnecessary however, as the first populated board worked well. This board is shown in Figure [2](#page-26-0).4.

Figure 2.4: Capacitive touch breakout with all components populated, before flux removal.

The first board was tested using the [Bus Pirate,](http://dangerousprototypes.com/docs/Bus_Pirate) a general purpose USB adapter that supports various serial protocols over a command line interface to the computer. This allowed me to power the board, configure it, and test it directly from my computer without flashing a microcontroller to perform the exchange. Since the [AT](#page-6-3)42 supports EEPROM storage of configuration, this also allowed me to program all settings before the board was installed in the system.

Figure 2.5: Capacitive touch electrodes.

The final part of the capacitive touch system is the electrode panel. The panel must have conductive pads wired to the input pins of the AT_{42} AT_{42} . This was achieved with thin copper foil, as shown in Figure [2](#page-26-1).5. The copper foil was cut to roughly the size of the desired buttons and a wire was soldered to the back of each electrode near the center. Then a small square of acrylic had holes drilled in it for the electrode wires to pass through, and the electrodes were glued to the surface. The wire holes in the back of the acrylic were then potted with hot glue as a strain relief. The finishing touch was gluing a paper sheet with the graphical buttons over the copper foil.

Overall the electrodes work very well, but are somewhat less sensitive than desired when placed behind the acrylic chassis. This could be corrected by making the button electrodes larger, and also by modifying the sense capacitors on the breakout board. As mentioned in the previous section, [Capacitive Touch,](#page-13-0) the sense capacitors were selected based on the recommended values in the datasheet due to time constraints.

2.2 firmware implementation & verification

2.2.1 *System Overview*

While most base level driver functionality was implemented in parallel with the hardware modules, the top level firmware design is a more all-or-nothing approach. Stages of development and testing were divided as possible, but due to the interdependencies of an integrated system these chunks of development were quite large.

2.2.2 *Scheduling Timer*

The scheduler, shown in Appendix [C.](#page-67-0)3, was implemented using timer set to a period of 5ms, and a counter that is incremented in the [ISR](#page-6-0) and used to determine when to dispatch services, using a bit addressable flag in the [AT](#page-6-5)89.

Timer 2 was used in 16 bit auto-reload mode set for an interval of 5ms. At each 5ms interval, a counter variable is incremented in the [ISR](#page-6-0), and XOR'd with its previous value. For those familiar with binary counting, each bit changes at a different frequency (e.g. the LSB changes at every increment, the LSB+1 changes at every other increment, LSB+2 at every 4th increment and so on). By XORing the count with itself, only the bits that change are returned. Each of these bits can then be OR'd with a bit addressable flag (to prevent clearing a flag that was already set), creating a set of flags that are set periodically at different multiples of the base frequency. A portion of this code is shown in Listing [2](#page-27-3).1. This is repeated through 8 bits to dispatch all 8 flags.

Listing 2.1: Snippet of Scheduler [ISR](#page-6-0)

```
1 // XOR the count with the previous count
2 xrl a,r7
3
4 // Set dispatch bits
5 setb _task_flag_0 // Task 0 gets set every ISR run
6 rrc A // Just waste bit 0 since it
           changes every time (for task 0)
7
8 rrc A // Rotate right into carry (
           b0 \rightarrow carry)9 orl C,_task_flag_1 // Or the flags together (ensure you
           don't clear something already set)
10 mov _task_flag_1,C // Set the flag
11 rrc A
12 orl C, task flag 2
13 mov \text{task}\text{-}\text{flag}\text{-}2, C
14 rrc A
```
Since the scheduler runs more frequently than any other piece of code in the system (except the stepper [ISR](#page-6-0), addressed later), it was optimized in assembly to reduce the load on the system. The original C version of the [ISR](#page-6-0) compiled to approximately 120 assembly instructions not including standard [ISR](#page-6-0) housekeeping instructions. The optimized routine takes just 20 assembly instructions, a reduction of over 80%.

The dispatch timing was verified using a helpful trick in the Linux command line:

cat /dev/ttyx | ts -i -m %.s

This command shows the output from serial device ttyx (where x should be a number) with a timestamp of the number of seconds elapsed since the last newline character was printed. This is especially useful for timing code execution on a microcontroller by placing a *putchar(*

n) at each point where time should be printed. Since *putchar* is generally a very lightweight function, this allows for timing of execution with minimal interference with the execution of the program as long as measurement points are far enough apart to prevent blocking while waiting for the last transmission to complete.

The scheduler in main takes the form of a series of if else if statements, a few of which are shown in snippet [2](#page-28-0).2. Else if's are used to implement a pseudo priority order between the service, which follows Rate Monotonic³ scheduling policy. While the scheduler is not preemptive, this does mean that the highest priority task ready to run when the system is idle will get to run. Note that these if statements are compiled as an atomic flag check and clear, which avoids the need for a critical section.

Listing 2.2: Snippet of Main Scheduler

³ Rate Monotonic specifies that the highest frequency task gets the highest priority

```
1 if(task_flag_0) 1/1x sched_period
\overline{2} {
3 task_flag_0 = 0;
4 // Calculates step timing for the stepper
5 stepper_sequence_generator();
6 }
7 else if(task_flag_1) \frac{1}{2} // 2x sched_period
8 {
9 \mid task_flag_1 = 0;
10 10 // Reads button states and puts them in the
                    buffer
11 task_buttons();
\begin{array}{c} \texttt{12} \end{array} }
```
2.2.3 *User Interface State Machine*

The design of the user interface state machine was detailed thoroughly in Section [1](#page-16-0).2.3, so that will not be repeated here. A brief pseudocode version of the service is offered below in snippet [2](#page-29-1).3.


```
1 | ring-remove(button_events)
 2 \mid \text{if}(\text{no}\_\text{button}\_\text{events})3 \mid \{4 idle_counter++ 1 and 1 and
                    counter
 5 if(idle_counter)
 6 {
 7 system_state = sleep; // Go to sleep if idle for
                               too long
 8 }
 9 \mid \}10 | switch(system_state)
11 {
12 case system_states:
13
14 // Implementation of state machine
15
16 }
```
The full code implementation of the user interface state machine can be seen in Appendix [C.](#page-50-0)2, lines 463-629. Due to the nature of this module, there is not much that can be done in the way of block level verification, so verification of this module was performed during system level testing.

2.2.4 *Display Task & LCD Driver*

The first implemenation of the display task simply updated all text on the [LCD](#page-6-4) at every dispatch based on the values present in the system state variable. As system level testing started to reveal that the system was overloaded, this was revised to mostly eliminate [LCD](#page-6-4) updates except where the values on the screen need to change.

This was achieved through a flag from the user interface task, which notifies the display task when the user changes the preset, requiring the update of preset names and values. The display task also monitors the system state to determine when the timer value needs to be updated and when it can be left static.

The display task utilizes an [LCD](#page-6-4) driver that was written for the course on a previous assignment, so it will not be detailed here. The display task code can be seen in Appendix [C.](#page-50-0)2 lines 354-460.

Another part of the optimization of the display task was the creation of a custom string formatting function, called micro_sprintf. This is an assembly optimized sprintf that only supports the conversion of unsigned 8 bit numbers to ASCII characters. This function can be seen in Appendix [C.](#page-50-0)2 lines 741-790.

The optimization efforts on the display task led to an overall execution time reduction from 32ms to execution times ranging from 15ms down to .07ms⁴ .

2.2.5 *Step Generator & Output Routine*

Section [1](#page-17-1).2.5 details the design of the stepper system. From the design, one can tell that the module was originally intended to be non-blocking, allowing other tasks to execute in the times in between step planning. In practice, this did not prove feasible due to overloading the system. During system level testing, the stepper would often stop when reaching a high speed as the [ISR](#page-6-0) catches the step generator and runs out of steps to execute. This was remedied with four changes: heavily optimizing the stepper [ISR](#page-6-0), reducing the number of steps per millimeter⁵, decreasing the speed⁶, and making the step generation routine blocking. The step generation routine now takes control of the processor and executes alone until all requested movements are completed.

This module was by far the most difficult and time consuming to write. Fortunately, it could be tested in seclusion without the other modules. Figure [2](#page-31-0).6 shows steps being captured for a short positive move, and then a short negative move. While the details are not easy to see in the image,

⁴ Execution time is much more variable now since the whole display is no longer updated. The worst case of 15ms happens only when changing presets

⁵ Changing the [DRV](#page-6-2) microstepping setting from 1/16 to 1/4

⁶ Also beneficial in reducing the noise the system makes, which was considerable at high speed

it is possible to see the change in the pulse density while the stepper accelerates and then decelerates.

Figure 2.6: Step generation capture. Captured with a generic Cypress FX2 logic analyzer and sigrok/PulseView at 24MHz.

Figure [2](#page-31-1).7 shows data captured from a short low speed movement and plotted to determine velocity throughout the move. Here the exponential velocity profile can be seen which results from using time division based acceleration⁷ . This profile is actually desirable since it reduces the instantaneous acceleration experienced by the motor (and egg).

Figure 2.7: Plot of stepper movement showing velocity profile and distance. Note that the capture is truncated before the move is complete.

The stepper [ISR](#page-6-0) was another area of intense assembly level optimization. The first iteration used a ring buffer in XDATA memory to store the step times, and was completely written in C. This version compiled to 453 assembly instructions. Given a max step rate of 2500⁸ steps per second, this [ISR](#page-6-0) needs to execute 1.1 million instructions per second to keep up, not

⁷ Discussed in Section [1](#page-17-1).2.5

^{8 25} steps/mm, 100mm/s

even including the step generation routine. The [AT](#page-6-5)⁸⁹ running at 11.0592 MHz can only execute 921 thousand instructions per second⁹, meaning we've already overrun. At this point the [ISR](#page-6-0) was thoroughly optimized, switching to a double buffer in directly addressable memory rather than the ring buffer in XDATA, and rewriting the routine in assembly. The final routine is just 52 instructions total, and most paths through the [ISR](#page-6-0) are significantly less than that. This equates to a reduction of 88%.

With the new [ISR](#page-6-0), achieving the step rate of 2500 steps/second takes just 130 thousand instructions per second, leaving 85% of the processor time to complete other tasks, like step planning. The stepper code is available in Appendix [C.](#page-71-0)6.

2.2.6 *Button Task & Capacitive Touch Driver*

The button task and capacitive touch driver are relatively simple. The driver provides wrappers for the two operations required: configuring the board and polling the buttons states as seen in Snippet [2](#page-32-2).4. One interesting thing to note that was discovered during test, the capacitive touch chip was not storing its configuration in EEPROM. It is not clear if this was due to an error in the routines used to program the EEPROM, or if this was a defect with the part. To resolve this, the critical settings are reprogrammed at every system boot. The full code is available in Appendix [C.](#page-88-0)11.

Listing 2.4: Snippet of Capacitive Touch Driver.

```
1 // Configure the captouch IC AT42QT1110, verify status is good
2 \vert void captouch_configure(void);
3
4 // Get the status of all buttons. If there is a failure this will
      return 0
\frac{1}{5} button_t captouch_poll_buttons(void);
```
The button task uses a basic state machine to detect the end of a button press and report it into the button event ring buffer. The end of the button press is reported rather than the start because it allows detection of long presses. The original user interface concept called for some extra functions that would be accessible through long presses, but these were not implemented due to schedule restrictions. The full button task is available in Appendix [C.](#page-50-0)2 lines 191-242.

2.2.7 *Thermal Control & ADC Driver*

The temperature readings are taken by the [ADC](#page-6-9) driver, and converted to Fahrenheit by the thermistor functions. [ADC](#page-6-9) readings are seperated from the thermal control task because in an earlier version of the code, the [ADC](#page-6-9) was oversampled. This proved unnecessary however, because of the

⁹ All assuming single cycle instructions

very long time constant of the system and heavy filtering of the thermistor voltage.

Temperature calibration was verified by measuring the temperature of boiling water and that of iced water. While a two point calibration is not ideal, no high resolution thermometer was available at the time to perform a more thorough calibration. The full code for the [ADC](#page-6-9) driver and thermistor conversion functions can be viewed in Appendix [C.](#page-91-0)13 and [C.](#page-94-0)15 respectively.

Thermal control, as mentioned in Section [1](#page-19-0).2.7, is based on a modified bang-bang controller. This controller was implemented to attempt to reduce setpoint overshoot observed with a traditional bang-bang controller, while avoiding cycling the relay too often. A data capture for a modified bang-bang run is shown in Figure [2](#page-33-1).8.

This plot shows the extreme amount of overshoot in the system, most likely due to a large thermal mass in the heater relative to the mass of the water, and poor water circulation. The modified bang-bang control is adequate in reducing this overshoot for the time being however. The full thermal control code can be seen in Appendix [C.](#page-50-0)2 288-352.

Figure 2.8: Plot of temperature and relay output for a heating run with a target temperature of 120 °F.

2.2.8 *Timer Task*

The timer task is very simple. At every dispatch it checks if the timer is enabled, and, if so, adds time to the current time value. This was optimized further at the assembly level to make use of the [BCD](#page-6-13) instructions available. The [BCD](#page-6-13) adjusts instruction drives the design of the timer to count up, rather than down, since the instruction only supports addtion. Unfortunately no side by side profiling of this function and its original C implementation was performed. The full code for the Timer is available in Appendix [C.](#page-50-0)2 lines 244-286.

2.2.9 *Endstop Interrupt Service Routine*

The endstop is possibly the simplest of all the software modules. It simple raises a flag when the endstop is triggered. Later, an additional line was added to stop the step generation timer. This stops the stepper motor if the endstop is hit unexpectedly. The full code can be seen in Appendix [C.](#page-83-0)7.

2.3 system level verification

Hardware assembly was a daunting task, as all the components had to be assembled without inadvertently breaking something after every component had been verified. Assembly was completed one module at a time, interspersed with quick tests I had created earlier in development. This allowed me to confirm each component in the system was functioning successfully before moving on to the next one. System level issues are notoriously difficult to find, so this approach helped limit surprises.

System level firmware verification was a challenging task, but eased significantly by the unit level tests performed during the rest of development. Task execution was verified using individual putchar() commands in each section of the scheduler. This allowed me to quickly profile which tasks were running and how often, and was instrumental in diagnosing the stepper stall issues that plagued early integration.

One major issue cropped up late in implemenation that was very difficult to diagnose. Just before I was due to demonstrate the system, I unplugged the programmer from the board and installed the bottom of the enclosure. Suddenly, the capacitive touch pad became unresponsive and registered random touches when not being touched. After reconnecting the programming cable to the system for debugging, the problem disappeared. Eventually I discovered that the problem is triggered by disconnecting the system from earth ground. When the programmer is connected, the system is grounded through the computer. When it is disconnected, the system is transformer isolated by the power supply. While the cause of this issue has not yet been identified, I hope to continue to work on it after the course is complete.

3.1 lessons learned

Below is a list of my favorite lessons learned through the course of the project

incremental development Breaking the project up into modules from the hardware and software block diagram was invaluable. For every untested module added, the number of potential issues in a system goes up exponentially, and system level issues are much more difficult to find than module level issues. By completing each module and testing it before integrating it, it is much less likely that system level issues will exist. If issues do arise, already available working known, working tests can be run on the integrated system to help pinpoint that issue.

incremental integration By the same logic as above, do not add all the parts to the final system at the same time, even if they have been individually tested. Instead, add modules to the system one by one, testing the test after each new addition. This may seem like a waste of time, but it only takes one difficult issue to more than offset all the time saved by skipping tests.

connectors Every cable that goes between two [PCB](#page-6-7)s should have a connector on it. These are clearly boundaries between two modules, and the ability to disconnect them will greatly ease debugging.

DON'T WAIT TO DEBUG Trying to guess the source of a problem and changing random things, instead taking out the oscilloscope, is a waste of time. Use the debugging tools available immediately, and keep systematic notes of what is changed while debugging. You never know what hasty change might make or break the system, and having the notes to backtrack changes to a working system is valuable.

streamline build process Spend the time up front to make a nice build environment for yourself. Create automation scripts, write a nice makefile, explore parallel compilation. You will be compiling and flashing code potentially hundreds of times. Make it painless.

sdcc SDCC is not perfect and often leaves a lot of room for assembly level optimization. Do not be intimidated by assembly level optimization.
procrastination Do not wait to start. It is very rare that a task takes less time than expected.

3.2 future developments

Here area a few areas of potential improvement in the project's future.

stepper optimization Improve the stepper planning routine and make it cooperative again. Currently it blocks execution, which can sometimes leave the relay on for a few seconds longer than intended driving the system far off the temperature set point.

code optimization Profile the system code, and optimize the most frequently called functions, likely at the assembly level. The system currently bogs down when heavily loaded, leaving the user interface with noticeable latency. Ideally this would be completely eliminated.

thermal control Improve the thermal control algorithm, most likely using a predictive heating model. By measuring the response of the system to a known length heat input pulse, I think I can estimate the amount of water present in the kettle. Using this, it should be possible to predict how long a heat input pulse is required to heat the water to the set point. This could greatly reduce overshoot without requiring the relay to cycle frequently.

capacitive touch Find the root cause of the capacitive touch earth ground issue and resolve it. Not a lot to say for this one.

interface extensions Extend the user interface to allow the programming of custom preset times and temperatures. These can be stored in the on board EEPROM to preserve them through power cycles.

mechanical improvements The acrylic case could be thickened and reinforced to make the system more robust for daily use.

3.3 conclusion

This project covered the creation of a single axis, controlled temperature bath, egg cooking robot from design, through implementation, and testing. Several notable issues were encountered through the course of the project, namely system overload due to the stepper pulse output routine, thermal control overshoot, and capacitive touch issues. Overall the project was a success, resulting in a system that can cook eggs and make tea, albeit noisily.

A C K N OW LED G MENTS

I'd like to thank my girlfriend, Cathy Gibson, for allowing me to use her as an excuse to build a ridiculous egg cooking robot, supporting me throughout the process, and proofreading this paper. I know you love listening to me rant about interrupt service routines, and don't worry because there is more to come.

I'd also like to thank Professor Linden McClure, for whose class this project was created. I appreciate the chance to follow a silly idea to its end.

One more thank you for the teaching assistants for [ESD](#page-6-0), for their help and guidance throughout the semester.

A big thanks to André Miede, who created this LATEXtemplate. It is licensed under the [GNU GPL](https://www.gnu.org/licenses/licenses.html) and used with permission.

<https://bitbucket.org/amiede/classicthesis/>

BILL OF MATERIALS

The table below contains all the items I purchased for this project, and some that I already had. Note that this does not reflect how much I paid, but common prices I was able to find online. The list also does not include some miscellaneous items like fasteners and bearings, which I already had on hand and do not have a good price estimate for.

Table A.1: Parts, costs, and quantities.

B

S CHEMATICS

This appendix includes only the new code written for this project. See the [table of contents](#page-3-0) for links to each file.

Listing C.1: Pin Settings Header

```
1 /* ====== PROGRAM INFO ====== */
2 // Dominic Doty
3 // ECEN 5613
4 // Final Project
5
6
7
8
9 /* ====== PIN MAPPING DEFINES ====== */
10
11 #define RELAY_OUT P1_0
12 #define I2C_SDA P1_1
13 #define I2C_SCL P1_2
14 #define STEP_STEP P1_3
15 #define STEP_DIR P1_4
16 #define SPI_MISO P1_5
17 #define SPI_SCK P1_6
18 #define SPI_MOSI P1_7
19
20 #define UART_RX P3_0
21 #define UART_TX P3_1
22 #define ENDSTOP P3_2
23 #define CS_CAPT P3_3
24 #define CS_ADC P3_4
25 #define STEP_SLP P3_5
```
Listing C.2: Main Source

```
1 /* ====== PROGRAM INFO ====== */
2 // Dominic Doty
3 // ECEN 5613
4 // Final Project
5
6
7 #include <sdcc-lib.h>
8 #include "mcs51/at89c51ed2 .h"
9 #include <string.h>
10
11 #define DEBUG_PRINT
12
13 #include "pin_map.h"
14 #include " serial .h"
15 #include "i2c .h"
16 #include "lcd_driver .h"
17 #include "adc_driver .h"
18 #include " thermistor .h"
19 #include "endstop .h"
20 #include "captouch_driver .h"
21 #include "delay .h"
22 #include "stepper .h"
23 #include "scheduler .h"
24
25
26 /* DEFINES */
27 #define AUXR_1024RAM_EXTRAM 0x0C
28 #define RELAY_OFF 0
29 #define RELAY_ON 1
30
31 /* Intertask Data */
32 typedef enum{
33 sleep,
34 home,
35 egg,
36 tea,
37 water,
38 run_heatup,
39 run_dropcar,
40 run_time,
41 run_raisecar,
42 run_water
43 }ui_state_t;
44
45 typedef struct
46 {
47 uint8_t temp_current; // current temp in F
48 uint8_t temp_goal; // target temp in F
49 bool temp_enable; // enable temperature control
50 uint8_t time_current[3];// BCD duration timer MM:SS.SS
```

```
51 uint8_t* time_goal; // BCD cooking time
52 bool time_enable; // Enable the timer
53 char* preset_name; // Name of the loaded preset
54 ui_state_t state; // Current UI state
55 ui_state_t restore_state;// Last active state before running
              program
56 ring_32_t button_events;// Holds events sent from captouch
57 bool preset_updated; // Flags if the preset choice or
              number has been updated by ui
58 uint8_t cursor_location;// Current location of the LCD cursor
59 }ui_situation_t;
60
61 ui_situation_t system_state;
62
63
64 /* PRESETS */
65 typedef struct
66 {
67 char name[10];
68 uint8_t temp;
69 uint8_t time[2];
70 }preset_t;
71
72 typedef struct
73 {
74 preset_t SQ_UL;
75 preset_t SQ_UR;
76 preset_t SQ_LL;
77 preset_t SQ_LR;
78 }mode_presets_t;
79
80 mode_presets_t egg_preset;
81 mode_presets_t tea_preset;
82 mode_presets_t water_preset;
83
84
85 /* TASK FUNCTIONS */
86 void task_buttons(void);
87 void task_timer(void) __naked;
88 void task_adc_samp(void);
89 void task_therm_control(void);
90 void task_display(void);
91 void task_ui(void);
92 void select_preset(button_t button, mode_presets_t* mode_preset);
93 void presets_initialize(void);
94 void micro_sprintf(__far char* destination, uint8_t number) __naked;
95
96
97 /* MAIN */
98 void main( void )
99 {
100 // Turn off the kettle just in case
```

```
101 RELAY_OUT = RELAY_OFF;
102
103 // Initialize the Presets
104 presets_initialize();
105
106 // Communications Init
107 serial_configure(BAUD_57600);
108 spi_configure(spi_ss_disable,
109 spi_mode_master,
110 spi_cpol_idle_high,
111 spi_cpha_sample_return_idle,
112 spi_baud_div8);
113
114 // Stepper System Init
115 stepper_configure();
116 endstop_configure();
117 stepper_sleep();
118
119 // LCD Init
120 lcd_configure();
121
122 // Peripherals Init
123 captouch_configure();
124 adc_configure();
125 i2c_reset();
126
127
128 // Tasks Init
129 ring_init(&system_state.button_events);
130
131 // Start Scheduler
132 scheduler_configure();
133
134 // Enable Global Interrupts
135 EA = 1;
136
137 printf_tiny("Initialization Complete\n");
138
139 // Run tasks as they're dispatched
140 while(1)
141 {
142 if(task_flag_0) // 1x sched_period
143 {
144 task_flag_0 = 0;
145 // Calculates step timing for the stepper
146 stepper_sequence_generator();
147 }
148 else if(task_flag_1) // 2x sched_period
149 {
150 task_flag_1 = 0;
151 // Reads button states and puts them in the
                     buffer
```

```
152 task_buttons();
153 }
154 else if(task_flag_2) // 4x sched_period
155 {
156 task_flag_2 = 0;
157 // And timer
158 task_timer();
159 // Do ADC reading here
160 task_adc_samp();
161 // Do relay control here
162 task_therm_control();
163 }
164 else if(task_flag_3) // 8x sched_period
165 {
166 task_flag_3 = 0;
167 // Do main state machine here
168 task_ui();
169 }
170 else if(task_flag_4) // 16x sched_period
171 {
172 task_flag_4 = 0;
173 // Do LCD updates here
174 task_display();
175 }
176 }
177 }
178
179 / * = == == \text{INIT INFO} == == */180 uint8_t _sdcc_external_startup()
181 {
182 AUXR = AUXR_1024RAM_EXTRAM;
                     // Configure XRAM
183 // CKCON0 = PCAX2 | T2X2 | T1X2 | T0X2 | X2; // Ramming
          Speed
184 return 0;
185 }
186
187
188
189 /* INLINE FUNCTIONS FOR TASKS */
190
191 void task_buttons(void)
192 {
193 // The cap touch board will only report one button at a time
194 // So if the button changes, we know its been released
195 // If it stays the same, we consider it a long press
196
197 // Stores the last button seen
198 static button_t last_button = NO_KEY;
199 static uint8_t seen_count = 0;
200
201 // Get most recently pressed button
```

```
202 button_t button = captouch_poll_buttons();
203
204 // Button handling plan
205 // last current action
206 // NO_KEY NO_KEY nothing
207 // key MO_KEY output the last key
208 // NO_key key hothing
209 // key key if ==, increment the
          key count, if key count > thresh, output
210 // if not equal
          output the last key
211
212 // Handle the buttons
213 if(button == NO_KEY)
214 {
215 // No active button
216 if(last_button != NO_KEY)
217 {
218 1218 // If last button was active, then we just
                    saw a falling edge
219 if(seen_count > LONG_TOUCH_MULTIPLIER)
220221 last_button += LONG_TOUCH_CODE;
222 }
223 ring_add_char(&system_state.button_events,
                    last_button);
224 }
225 seen_count = 0; // if we have an active no-key we can
               't be in a hold
226 }
227 else
228 {
229 // We have some active button
230 if(last_button == button)
231 {
232 // current button is the same as the last one
                    we sampled
233 seen_count++; // increment a counter to
                    catch long touches
234 if(seen_count > LONG_TOUCH_MULTIPLIER + 1)
235236 seen_count--; // this keeps
                         seen_count from rolling over
237 }
238 }
239 }
240
241 last_button = button; // Store for next time
242 }
243
244 void task_timer(void) __naked
245 {
```

```
246 // If the clock is running, add .02 seconds
247 // MM:SS.SS time[0, 1, 2]
248 248249 // Jump out if timer isn't enabled
250 mov dptr,#(_system_state + 0x0009)
251 movx a,@dptr
252 jz $00027
253
254 // Add .02 seconds to the clock (2 here since looking
               at hundreths)
255 mov dptr,#(_system_state + 0x0005)
256 movx a,@dptr
257 add a,#0x02
258 da a
259 movx @dptr,a
260
261 // Add carry to seconds
262 mov dptr,#(_system_state + 0x0004)
263 movx a,@dptr
264 addc a,#0x00
265 da a
266
267 // If equal to 60, gotta set back to zero and set
              carry
268 mov ac,c // cjne messes with carry so
              we need to save it
269 cjne a,#0x60,$00028
270 clr a
271 setb ac
272 $00028:
273 movx @dptr,a
274 mov c, ac
275
276 // Add carry to minutes
277 mov dptr,#(_system_state + 0x0003)
278 movx a,@dptr
279 addc a,#0x00
280 da a
281 movx @dptr,a
282
283 $00027:
284 ret
285 ___endasm;
286 }
287
288 void task_adc_samp(void)
289 {
290 // Read the current temperature and do a bit of moving
         average to smooth
291 system_state.temp_current = thermistor_convert(adc_reading(
         adc_mode_single, adc_channel_0));
292 }
```

```
293
294 void task_therm_control(void)
295 {
296 typedef enum {temp_goal_set, temp_pulse, temp_coast}
        temp_state_t;
297 static temp_state_t temp_state = temp_goal_set;
298 static uint8_t temp_coast_count;
299 static uint8_t local_goal;
300 static uint8_t last_temp;
301
302 if(system_state.temp_enable)
303 {
304 switch(temp_state)
305 {
306 case temp_goal_set:
307 // Calc setpoint
308 if(system_state.temp_current <
                    system_state.temp_goal)
309310 local_goal = system_state.
                        temp_current + (
                        system_state.temp_goal -
                        system_state.temp_current
                        ) / 4;311 temp_state = temp_pulse;
312 }
313 break;
314
315 case temp_pulse:
316 // Turn on till you reach that point,
                    then turn off
317 if(system_state.temp_current <
                    local_goal)
318319 RELAY_OUT = RELAY_ON;
320 }
321 else
322323 RELAY_OUT = RELAY_OFF;
324 temp_state = temp_coast;
325 }
326 break;
327
328 case temp_coast:
329 // Coast till level out
330 if(system_state.temp_current ==
                    last_temp)
331 {
332 temp_coast_count++;
333 }
334 else
335
```

```
336 temp_coast_count = 0;
337 last_temp = system_state.
                     temp_current;
338 }
339
340 if(temp_coast_count > 10)
341342 temp_coast_count = 0;
343 temp_state = temp_goal_set;
344 }
345 break;
346 }
347 }
348 else
349 {
350 RELAY_OUT = RELAY_OFF;
351 }
352 }
353
354 void task_display(void)
355 {
356 static ui_state_t lcd_last_state = home;
357
358 if(system_state.state == sleep)
359 {
360 lcd_clear();
361 lcd_last_state = sleep;
362 }
363 else
364 {
365 switch (system_state.state)
366 {
367 case egg:
368 if(lcd_last_state != egg)
369370 lcd_putstring(LCD_LINE_3, "
                     Status: Settings");
371 lcd_last_state = egg;
372 }
373 if(system_state.preset_updated)
374375 lcd_putstring(LCD_LINE_0, "
                     EGG: ";
376 lcd_putstring(LCD_LINE_0 + 6,
                      system_state.preset_name
                     );
377 }
378 break;
379
380 case tea:
381 if(lcd_last_state != tea)
382 {
```



```
452 lcd_data[2][6] = (system_state.time_current
                    [1] \& 0x0F) + '0';
453 lcd_putstring(LCD_LINE_2, lcd_data[2]);
454 }
455
456 // Update Current Temp
457 micro_sprintf(&lcd_data[0][3], system_state.
               temp_current);
458 lcd_putstring(LCD_LINE_1, lcd_data[0]);
459 }
460 }
461
462 void task_ui(void)
463 {
464 static uint8_t inactive_count = 0;
465
466 // Grab the latest pressed key (if there is none, present
          NO_KEY)
467 button_t button;
468 if(ring_remove_char(&system_state.button_events, &button) !=
          ERR_SUCCESS)
469 {
470 button = NO_KEY;
471
472 if( (system_state.state == egg) ||
473 (system_state.state == tea) ||
474 (system_state.state == water))
475 {
476 inactive_count++;
477 1f(inactive_count == 255)478 \{479 system_state.state = sleep;
480 }
481 }
482 }
483 else
484 {
485 inactive_count = 0;
486 }
487
488 // Switch through system state machine
489 switch(system_state.state)
490 {
491 case sleep:
492 stepper_sleep();
493 if(button != NO_KEY){system_state.state =
                    home; }
494 break;
495
496 case home:
497 system_state.time_enable = false;
498 system_state.temp_enable = false;
```

```
499 stepper_home();
500 system_state.state = egg;
501 select_preset(SQ_UL, &egg_preset);
502 break;
503
504 case egg:
505 if(button == PLAY)
506 {
507 system_state.restore_state = egg;
508 system_state.state = run_heatup;
509 }
510 else if (button == MODE)
511 {
512 system_state.state = tea;
513 select_preset(SQ_UL, &tea_preset);
514 }
515 else
516 {
517 select_preset(button, &egg_preset);
518 }
519 break;
520
521 case tea:
522 if(button == PLAY)
523 {
524 system_state.restore_state = tea;
525 system_state.state = run_heatup;
526 }
527 else if (button == MODE)
528 \{529 system_state.state = water;
530 select_preset(SQ_UL, &water_preset);
531 }
532 else
533 {
534 select_preset(button, &tea_preset);
535 }
536 break;
537
538 case water:
539 if(button == PLAY)
540 \{541 system_state.restore_state = water;
542 system_state.state = run_water;
543 }
544 else if (button == MODE)
545546 system_state.state = egg;
547 select_preset(SQ_UL, &egg_preset);
548 }
549 else
550
```

```
551 select_preset(button, &water_preset);
552 }
553 break;
554
555 case run_heatup:
556 if(button == STOP)
557558 system_state.temp_enable = false;
559 system_state.state = system_state.
                     restore_state;
560 return;
561 }
562
563 system_state.temp_enable = true;
564
565 if( (system_state.temp_current >=
                system_state.temp_goal - 1) &&
566 (system_state.temp_current <=
                     system_state.temp_goal + 3))
567 {
568 system_state.state = run_dropcar;
569 }
570 break;
571
572 case run_dropcar:
573 stepper_segment_add(-110, 20);
574 stepper_segment_add(-5, 0);
575 stepper_motion_enabled = true;
576 system_state.state = run_time;
577 break;
578
579 case run_time:
580 if(button == STOP)
581 {
582 system_state.state = run_raisecar;
583 return;
584 }
585
586 system_state.time_enable = true;
587
588 if( (system_state.time_current[0] >=
                system_state.time_goal[0]) &&
589 (system_state.time_current[1] >=
                     system_state.time_goal[1]))
590 {
591 system_state.state = run_raisecar;
592 }
593 break;
594
595 case run_raisecar:
596 stepper_segment_add(110, 20);
597 stepper_segment_add(5, 0);
```

```
598 stepper_motion_enabled = true;
599 system_state.time_enable = false;
600 system_state.temp_enable = false;
601 system_state.time_current[0] = 0;
602 system_state.time_current[1] = 0;
603 system_state.time_current[2] = 0;
604 system_state.state = system_state.
                   restore_state;
605 break;
606
607 case run_water:
608 if(button == STOP)
609 {
610 system_state.state = system_state.
                       restore_state;
611 system_state.temp_enable = false;
612 return;
613 }
614
615 system_state.temp_enable = true;
616
617 if( (system_state.temp_current >=
                   system_state.temp_goal - 1) &&
618 (system_state.temp_current <=
                       system_state.temp_goal + 3))
619 \{620 system_state.state = system_state.
                       restore_state;
621 system_state.temp_enable = false;
622 }
623 break;
624
625 default:
626 system_state.state = home;
627 break;
628 }
629 }
630
631 void select_preset(button_t button, mode_presets_t* mode_preset)
632 {
633 preset_t* preset;
634 switch (button)
635 {
636 case SQ_UL:
637 preset = \&(mode_{\text{p}} preset = \&(mode_{\text{p}} preset->SQ_UL);
638 break;
639
640 case SQ_UR:
641 preset = \&(mode_preset->SQ_UR);
642 break;
643
644 case SQ_LL:
```

```
645 preset = \&(mode_preset->SQ_LL);
646 break;
647
648 case SQ_LR:
649 preset = \&(mode_preset->SQ_LR);
650 break;
651
652 default:
653 preset = NULL;
654 break;
655 }
656
657 if(preset != NULL)
658 {
659 system_state.temp_goal = preset->temp;
660 system_state.time_goal = preset->time;
661 system_state.preset_name = preset->name;
662 system_state.preset_updated = true;
663 }
664 }
665
666 void presets_initialize(void)
667 {
668 //// EGGS
669 memcpy(egg_preset.SQ_UL.name, "Very Hard", sizeof("Very Hard"
            ));
670 egg_preset.SQ_UL.temp = 210;
671 egg_preset.SQ_UL.time[0] = 0 \times 09;
672 egg_preset. SQ_ULL.time[1] = 0x00;673
674 memcpy(egg_preset.SQ_UR.name, "Hard", sizeof("Hard"));
675 egg_preset.SQ_UR.temp = 200;
676 egg_preset. SQ_UIR.time[0] = 0x08;677 egg_preset.SQ_UR.time[1] = 0 \times 00;
678
679 memcpy(egg_preset.SQ_LL.name, "Medium", sizeof("Medium"));
680 egg_preset.SQ_LL.temp = 180;
681 egg_preset.SQ_LL.time[0] = 0 \times 10;
682 egg_preset.SQ_LL.time[1] = 0 \times 00;
683
684 memcpy(egg_preset.SQ_LR.name, "Soft", sizeof("Soft"));
685 egg_preset.SQ_LR.temp = 167;
686 egg_preset.SQ_LR.time[0] = 0 \times 12;
687 egg_preset.SQ_LR.time[1] = 0x00;
688
689
690 //// TEA
691 memcpy(tea_preset.SQ_UL.name, "Black ", sizeof("Black "));
692 tea_preset. SQL L. temp = 206;
693 tea_preset.SQ_UL.time[0] = 0x05;
694 tea_preset.SQ_UL.time[1] = 0x00;
695
```

```
696 memcpy(tea_preset.SQ_UR.name, "Oolong", sizeof("Oolong"));
697 tea_preset.SQ_UR.temp = 203;
698 tea_preset. SQ_UR.time[0] = 0x04;
699 tea_preset. SQ_UR.time[1] = 0x00;700
701 memcpy(tea_preset.SQ_LL.name, "White", sizeof("White"));
702 tea_preset.SQ_LL.temp = 185;
703 tea_preset. SQLL.time[0] = 0 \times 03;
704 tea_preset. SQL Lime[1] = 0x00;
705
706 memcpy(tea_preset.SQ_LR.name, "Herbal", sizeof("Herbal"));
707 tea_preset.SQ_LR.temp = 203;
708 tea_preset.SQ_LR.time[0] = 0x06;
709 tea_preset.SQ_LR.time[1] = 0x00;
710
711 //// WATER
712 memcpy(water_preset.SQ_UL.name, "Scalding ", sizeof("Scalding "
              ));
713 water_preset.SQ_UL.temp = 210;
714 water_preset.SQ_UL.time[0] = 0x00;
715 water_preset.SQ_UL.time[1] = 0 \times 00;
716
717 memcpy(water_preset.SQ_UR.name, "Less Hot", sizeof("Less Hot"
              ));
718 water_preset.SQ_UR.temp = 190;
719 water_preset.SQ_UR.time[0] = 0x00;
720 water_preset.SQ_UR.time[1] = 0x00;
721
722 memcpy(water_preset.SQ_LL.name, "Warm", sizeof("Warm"));
723 water_preset.SQ_LL.temp = 150;
724 water_preset.SQ_LL.time[0] = 0x00;
725 water_preset.SQ_LL.time[1] = 0x00;
726
727 memcpy(water_preset.SQ_LR.name, "Tepid", sizeof("Tepid"));
728 water_preset.SQ_LR.temp = 120;
729 water_preset.SQ_LR.time[0] = 0x00;
730 water_preset.SQ_LR.time[1] = 0x00;
731
732 //// Clear the time
733 system_state.time_current[0] = 0;
734 system_state.time_current[1] = 0;
735
736
737 //// Flag the Display to Update
738 system_state.preset_updated = true;
739 }
740
741 void micro_sprintf(__far char* destination, uint8_t number) __naked
742 {
\frac{743}{743} // // Only prints 8 bit numbers to a buffer
744 // uint8_t hund = number/100;
745 // number -= hund*100;
```

```
746 // uint8_t tens = number/10;
747 // number -= tens*10;
748
749 // destination[0] = hund + '0';
750 // destination[1] = tens + '0';
751 // destination[2] = number + '0';
752
753 // Suppress compiler warning about unused variables
754 destination;
755 number;
756
757 // dptr holds destination address
758 // number is at #_micro_sprintf_PARM_2 and in A
759 200760 push b
761
762 mov b, #100 // Div by 100
763 div ab // A has the 100's
          place, b has the remainder
764 add a,#0x30 // Shift into ascii number
          range
765 movx @dptr, a // Store it
766 inc dptr // Move address pointer
767 mov a,b a,b // Move remainder to
         A
768
769 mov b, #10 // Div by 10
770 div ab // A has the 10's
          place, b has the 1's
771 add a,#0x30 // Shift into ascii number
          range
772 movx @dptr, a // Store it
773 inc dptr // Move address pointer
774 mov a,b a,b // Move remainder to
         A
775
776 add a,#0x30 // Shift into ascii number
          range
777 movx @dptr, a // Store it
778 inc dptr // Move address pointer
779
780 mov a,#'F' // 'F' for degrees F
781 movx @dptr, a // Store it
782 inc dptr // Move address pointer
783
784 clr a // Null
785 movx @dptr, a // Store it
786
787 pop b
788 ret
789 __endasm;
790 }
```
Listing C.3: Scheduler Header

```
1 /* T2 AS TASK SCHEDULER */
2 // Dominic Doty
3 // ECEN 5613
4
5
6 #ifndef SCHEDULER_H
 7 #define SCHEDULER_H
8
9 /* INCLUDES */
10 #include <stdint.h>
11 #include <stdio.h>
12 #include "mcs51/at89c51ed2 .h"
13 #include "pin_map.h"
14 #include " timer_driver .h"
15
16
17 /* DEFINES */
18 #define PERIPH_CLK_FREQ 11059200
19 #define CLK_PER_TICK 12
20 #define MS_PER_S 1000
21
22 /* TYPEDEFS */
23 // Div2 range is .002-142 ms
24 // Div6 range is .007-426 ms
25 typedef enum{
26 periph_clk_div6 = 0b00000000,
27 periph_clk_div2 = 0b00000010,
28 t_zero = 0b00000100,
29 ext_int = 0b00000110
30 }scheduler_base_freq_t;
31
32
33 /* GLOBALS */
34 extern volatile __bit task_flag_0; // Flags for each service
       period requested
35 extern volatile __bit task_flag_1;
36 extern volatile __bit task_flag_2;
37 extern volatile __bit task_flag_3;
38 extern volatile __bit task_flag_4;
39
40
41 /* PROTOTYPES */
42 // Set up Timer 2 as a scheduler, running at an interval of base
       period (ms)
43 // tasks are dispatched in binary multiples
44 // t0 every base period, t1 every 2x base period, t2 every 4x base
       period, etc.
45 void scheduler_configure(void);
46
47 // PCA ISR sets schedule flags when each period expires
```

```
48 void scheduler_ISR(void) __interrupt(TF2_VECTOR) __naked;
49
```
#endif // SCHEDULER_H

```
Listing C.4: Scheduler Source
```

```
1 /* T2 AS TASK SCHEDULER */
2 // Dominic Doty
3 // ECEN 5613
4
5
6 /* INCLUDES */
7 #include "scheduler .h"
8
9
10 /* DEFINES */
11 #define TICKS_PER_MS 9216
12
13
14 /* TYPEDEFS */
15
16
17 /* GLOBALS */
18 volatile __bit task_flag_0 = 0; // Flags for each service period
      requested
19 volatile \_bit task_flag_1 = 0;
20 volatile \_bit task_flag_2 = 0;
21 volatile \_bit task\_flag_3 = 0;
22 volatile \_bit task\_flag_4 = 0;
23
24 uint8_t int_count = 0;
25
26 /* FUNCTION DEFINITIONS */
27 void scheduler_configure(void)
28 {
29 // AUTORELOAD
30 // Set for .005s period
31 T2CON = 0 \times 80;
32 RCAP2H = 0xEE;
33 RCAP2L = 0 \times 00;
34 TL2 = RCAP2L;
35 TH2 = RCAP2H;
36
37 // Int setup and run
38 ET2 = 1; // Enable overflow interrupt
39 TR2 = 1; // Run
40 }
41
42 void scheduler_ISR(void) __interrupt(TF2_VECTOR) __naked
43 {
44 __asm
45 // Stack Regs
```

```
46 push acc
47 push dpl
48 push dph
49 push ar7
50 push psw
51 mov psw,#0x00
52
53 // Clear Int Flag
54 clr _TF2
55
56 // Get the ISR count and increment it
57 mov dptr,#_int_count
58 movx a,@dptr
59 mov r7,a
60 inc a
61 movx @dptr,a
62
63 // XOR the count with the previous count
64 xrl a,r7
65
66 // Set dispatch bits
67 setb _task_flag_0 // Task 0 gets set every ISR run
68 rrc A // Just waste bit 0 since it
          changes every time (for task 0)
69
70 rrc A // Rotate right into carry (
          b0 -> carry)
71 orl C,_task_flag_1 // Or the flags together (ensure you
          don't clear something already set)
72 mov _task_flag_1,C // Set the flag
73 rrc A
74 orl C,_task_flag_2
75 mov _task_flag_2,C
76 rrc A
77 orl C,_task_flag_3
78 mov _task_flag_3,C
79 rrc A
80 orl C,_task_flag_4
81 mov _task_flag_4,C
82
83 // Restore Regs
84 pop psw
85 pop ar7
86 pop dph
87 pop dpl
88 pop acc
89 reti
90
91 __endasm;
92 }
```
Listing C.5: Stepper Motor Driver Header

```
1 /* STEPPER EXECUTION CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 #ifndef STEPPER_H
6 #define STEPPER_H
7
8 /* INCLUDES */
9 #include <stdint.h>
10 #include <stdio.h>
11 #include <stdbool.h>
12 #include "mcs51/at89c51ed2 .h"
13 #include "pin_map.h"
14 #include " timer_driver .h"
15 #include " ring_buffer .h"
16 #include "endstop .h"
17
18 /* DEFINES */
19 // Debug enable
20 // #define DEBUG_PRINT
21 // #define DEBUG_ASM_CHAR
22 #include "debug.h"
23
24 // Motion settings
25 #define STEP_PER_MM 25
26 #define STEP_ACCEL_DIV 32 // Bigger means slower,
       smaller means faster, use powers of 2 for optimization
27 #define STEP_HOME_V 150 // mm/s
28 #define STEP_HOME_BACKOFF 2 // mm
29 #define STEP_TICKS_PER_S 921600 // timer ticks per 1 second
30
31 /* TYPEDEFS */
32
33
34 /* GLOBALS */
35 extern __bit stepper_motion_enabled;
36
37 /* PROTOTYPES */
38 // Configure Timer 1 and ring buffers
39 void stepper_configure(void);
40
41 // Add motion segments to the stepper queue
42 // dx is delta x in mm, vf is the desired final speed in mm/s
43 // the planner immediately tries to speed up to vf.
44 // If the segment isn't long enough to hit vf with specified accel,
45 // top speed will be arbitrary
46 void stepper_segment_add(int8_t dx, uint8_t vf);
47
48 // Takes segments from above function and turns them into timer
       intervals for the ISR
```

```
49 void stepper_sequence_generator(void);
50
51 // Put stepper to sleep (stops annoying noise)
52 void stepper_sleep(void);
53
54 // Home - drive into the endstop fast, then backoff, then slow. Sets
       system zero
55 // This is the only way to exit stepper sleeping state - since
       position is unknown as soon as you sleep
56 // THIS IS BLOCKING
57 void stepper_home(void);
58
59 // ISR for executing steps
60 void stepper_isr(void) __interrupt(TF0_VECTOR);
61
62 #endif // STEPPER_H
```
Listing C.6: Stepper Motor Driver Source

```
1 /* STEPPER EXECUTION CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5
6 /* INCLUDES */7 #include "stepper .h"
8
9
10 /* DEFINES */
11 // These step times, when passed to the ISR, mean special things
12 #define STEP_CODE_STOP 0x00
13 #define STEP_CODE_UP 0x01
14 #define STEP_CODE_DOWN 0x02
15
16 // Stepper DIR pin convention
17 #define STEP_DIR_UP 0x01
18 #define STEP_DIR_DOWN 0x00
19
20 // Sleep convention
21 #define STEP_SLEEP_EN 0x00
22 #define STEP_SLEEP_DIS 0x01
23
24 // This velocity (ticks/step, inverse velocity) is considered not
      moving
25 #define STEP_MIN_VEL 0xFFFC
26
27 // Size of each double buffer must be even #
28 #define BUFFER_SIZE 16
29
30
31 /* TYPEDEFS */
32 typedef struct
```
```
33 {
34 int8_t dx; // delta mm
35 uint8_t vf; // final velocity of segment in mm/s
36 }stepper_segment_t;
37
38
39 /* GLOBALS */
40 __near uint8_t buffer_0[BUFFER_SIZE];
41 __near uint8_t buffer_1[BUFFER_SIZE];
42 __near uint8_t*
__near isr_index = buffer_0;
43 \_\_near uint8<sub>-</sub>t* \_\_near generator\_\_index = buffer\_\theta;
44
45 --bit use-buffer-0 = 0; // Set when ready for ISR to use, cleared
      when ISR is done
46 -bit use buffer 1 = 0;
47
48 ring_32_t step_seg_x;
49 ring_32_t step_seg_v;
50
51 \_bit stepper motion enabled = false;
52
53 /* STATIC FUNCTION DECLARATIONS */
54 err_t double_buffer_add(uint16_t number);
55
56
57 /* FUNCTION DEFINITIONS */
58 void stepper_configure(void)
59 {
60 ring_init(&step_seg_x);
61 ring_init(&step_seg_v);
62
63 STEP_STEP = 1;
64 STEP_DIR = 0;
65 STEP_SLP = STEP_SLEEP_EN;
66
67 timer_init(timer_0, sixteen_bit_mode, true, false, false, 1,
              false);
68 TR\theta = 0;69 }
70
71
72 void stepper_segment_add(int8_t dx, uint8_t vf)
73 {
74 ring_add_char(&step_seg_x, dx);
75 ring_add_char(&step_seg_v, vf);
76 }
77
78
79 void stepper_sequence_generator(void)
80 {
81 if(!stepper_motion_enabled)
82 {
```

```
83 return;
84 }
85
86 debug_print("Seqgen started\n", 0);
87
88 // Holds the segment we're currently working on
89 static stepper_segment_t command = {0,0};
90
91 // Current stepper velocity (inverse, ticks/step)
92 static uint16_t current_v = STEP_CODE_STOP;
93
94 err_t error;
95 static __bit direction_set = false; // Stores if we've
           set the movement direction
96 static int16_t dx_steps = 0; 96 // Stores the delta X
           move in steps instead of mm
97 static uint16_t vf_steps = 0; // Stores the final V
           of the segment in ticks/step
98
99 // Blocks while planning till all moves in the buffer are
           exhausted and the move is done
100 while(1)
101 {
102 // Translates to atomic JBC
103 if(endstop_flag)
104 {
105 endstop_flag = 0;
106
107 // Reset - dump buffers, stop ISR, reset
                      sequence state
108 TR0 = 0;
109 ring_init(&step_seg_x);
110 ring_init(&step_seg_v);
111 direction_set = false;
112 stepper_motion_enabled = false;
dx_{\text{113}} dx_steps = 0;
114 stepper_home();
115 return;
116   }
117
118 // If we don't have a command to work on yet, grab
                one
119 if(dx\_steps == 0)120 \{121 debug_print("Get cmd\n", 0);
122
123 ring_remove_char(&step_seg_x, &command.dx);
124 debug_print("dxmm="/d\n", command.dx);
125
126 error = ring_remove_char(&step_seg_v, &
                      command.vf);
127 debug_print("Vfmm="\alpha), command.vf);
```

```
128
129 if(error != ERR_SUCCESS)
130 {
131 // No more segments, quit
132 debug_print("No seg\n", 0);
133 stepper_motion_enabled = false;
134 direction_set = false;
135 current_v = 0;136 return;
137 }
138
139 dx_steps = command.dx * STEP_PER_MM;
140 if(command.vf == 0)
141 \{142 vf_steps = STEP_MIN_VEL;
143 }
144 else
145 {
146 vf_steps = (STEP_TICKS_PER_S/
                   STEP_PER_MM)/command.vf;
147 }
148
149 debug_print("dx=%d vf=%u\n", dx_steps,
               vf_steps);
150 }
151
152 // If we weren't able to set the direction yet
153 if(direction_set == false)
154 {
155 debug_print("Dir:\n\begin{pmatrix}\n1 & 0 \\
1 & 0\n\end{pmatrix};
156 // Set the direction of movement for the new
               command
157 if(dx\_steps > 0)158 {
159 // Moving "forwards"
160 // Put the "forwards" code into the
                   step time buffer
161 error = double_buffer_add(
                   STEP_CODE_UP);
162 if(error != ERR_SUCCESS)
163 {
164 TR0 = 1;
165 continue; // Stop if
                       the buffer is full
166 }
167 direction_set = true;
168 debug_print("Dir FW\n", 0);
169 }
170 else
171 {
172 // Moving "backwards"
```

```
173 // Put the "backwards" code into the
                     step time buffer
174 error = double_buffer_add(
                     STEP_CODE_DOWN);
175 if(error != ERR_SUCCESS)
176 \{177 TR0 = 1;
178 continue; // Stop if
                         the buffer is full
179 }
180 direction_set = true;
181 debug_print("Dir RV\n", 0);
182 }
183 }
184
185 // If we're not moving, set velocity to min
186 if(current_v == STEP_CODE_STOP)
187 {
188 current_v = STEP_MIN_VEL;
189 debug_print("V=0, set slow\n", 0);
190 }
191
192 // Loop generating till full
193 while(dx_steps != 0)
194 {
195 error = double_buffer_{add}(-current_v); //
                 Add to step buffer
196 if(error != ERR_SUCCESS)
197 {
198 debug_print("Bf full\n", 0);
199 TR0 = 1;
200 continue; // Stop if the buffer
                     is full
201  }
202
203 dx_steps > 0 ? dx_steps-- : dx_steps++; //
                 decrement the number of remaining steps
204
205 if(current_v > vf_steps)
206 {
207 // Speed up
208 208 // Increase the velocity by the
                     accelerator (inverse velocity,
                     remember)
209 current_v -= current_v/STEP_ACCEL_DIV
                     ;
210
211 211 // If we overshot velocity, pin back
                     to the specified V
212 if(current_v < vf_steps)
213 \{214 current_v = vf_steps;
```


```
258 void stepper_sleep(void)
259 {
260 STEP_SLP = STEP_SLEEP_EN;
261 }
262
263 void stepper_home(void)
264 {
265 // Set the endtop flag if the endstop is already triggered
266 if(ENDSTOP == 0)
267 {
268 endstop_flag = 1;
269 }
270
271 // Wake the stepper driver
272 STEP_SLP = STEP_SLEEP_DIS;
273
274 // Fast Home
275 debug_print("fast home enter\n",0);
276 STEP_DIR = STEP_DIR_UP;
277 while(1)
278 {
279 debug_print("stp\n",0);
280 // Do a step
281 STEP_STEP = 0;
282 282283 NOP
284 NOP
285 NOP
286 NOP
287 \qquad \qquad __endasm;
288 STEP_STEP = 1;
289
290 // This translates to an atomic check/clear JBC
291 if(endstop_flag)
292 {
293 endstop_flag = 0;
294 break;
295 }
296
297 // Twiddle to create the right timing for homing
               speed
298 for(uint16_t i = 0; i<(1000000/(STEP_HOME_V *
               STEP_PER_MM)); i++)
299 {
300 __asm
301 NOP
302 __endasm;
303 }
304 }
305
306 // Backoff
307 debug_print("backoff enter\n",0);
```

```
308 STEP_DIR = STEP_DIR_DOWN;
309 while(ENDSTOP == 0)
310 {
311 // Do a step
312 debug_print("stp\n",0);
313 STEP_STEP = 0;
314 __asm
315 NOP
316 NOP
317 NOP
318 NOP
319 __endasm;
320 STEP_STEP = 1;
321
322 // Twiddle to create the right timing for homing
                  speed
323 for(uint16_t i = 0; i<(1000000/(STEP_HOME_V *
                  STEP_PER_MM)); i++)
324 \{325 \_asm
326 NOP
327 \qquad \qquad328 }
329 }
330 }
331
332 // Double Buffers
333 void stepper_isr(void) __interrupt(TF0_VECTOR) __naked
334 {
335 \qquad -asm
336 jb _endstop_flag,00065$
337 sjmp 00067$ // No endstop
338 00065$: // Endstop
339 reti
340
341 // Stack used registers
342 00067$:
343 push acc
344 push ar0
345 push psw
346 mov psw,#0x00
347
348 // Stop the timer to prevent accidental rollovers
                  while reloading
349 clr _TR0
350
351 // Load r0 with pointer
352 mov r0,_isr_index
353
354 // Check for direction change code
355 cjne @r0,#(STEP_CODE_UP>>8),00001$ //if the high
                   byte doesn't match, jump
```



```
436 asm_put( 'p', 00093$)
437 mov _isr_index,r0
438 sjmp 00011$
439
440 // Stop Moving and disable the timer
441 00010$:
442 asm_put( 'q', 00092$)
443 mov _isr_index,#_buffer_0 // Reset the pointer
444 clr _use_buffer_0 // Reset the
              buffer use flags
445 clr _use_buffer_1
446 clr TR0 //
              Stop the timer
447
448
449 // Restore state
450 00011$:
451 asm_put( 'e ', 00091$)
452 pop psw
453 pop ar0
454 pop acc
455 reti
456 ___endasm;
457 }
458
459
460 err_t double_buffer_add(uint16_t number)
461 {
462 // Check for space
463 if(generator_index == &buffer_0[BUFFER_SIZE])
              // buffer_0 full
464 {
465 use_buffer_0 = 1;
                        // flag buffer_0 full
466 if(use_buffer_1 == 0)
                   // buffer_1 empty
467 {
468 debug_print("buffer o full, sw to 1\n",0);
469 generator_index = buffer_1; // Next
                    buffer is empty and this ones full,
                    switch
470  }
471 else
472 {
473 debug_print("both full\n",0);
474 return ERR_FULL;
475 }
476 }
477 else if(generator_index == &buffer_1[BUFFER_SIZE]) //
         buffer_1 full
478 {
```

```
479 use_buffer_1 = 1;
                          // flag buffer_1 full
480 if(use_buffer_0 == 0)
                     // buffer_0 empty
481 {
482 debug_print("buffer 1 full, sw to 0\n", 0);
483 generator_index = buffer_0; // Next
                     buffer is empty and this ones full,
                     switch
484 }
485 else
486 {
487 debug_print("both full\n",0);
488 return ERR_FULL;
489 }
490 }
491
492 // Add stuff to buffer since there's space
493 debug_print("added %u\n", number);
494 *generator_index = number>>8;
495 generator_index++;
496 *generator_index = number;
497 generator_index++;
498
499 return ERR_SUCCESS;
500 }
```
Listing C.7: Enstop Header

```
1 /* ENDSTOP ISR */
2 // Dominic Doty
3 // ECEN 5613
4
5
6 #ifndef ENDSTOP_H
7 #define ENDSTOP_H
8
9 /* INCLUDES */
10 #include <stdint.h>
11 #include <stdio.h>
12 #include "mcs51/at89c51ed2 .h"
13 #include "pin_map.h"
14
15 /* GLOBALS */
16 extern volatile __bit endstop_flag;
17
18 /* PROTOTYPES */
19 // Setup INT0 for negative edge interrupt, set to input mode
20 void endstop_configure(void);
21
22 // Handle the endstop interrupt, set flag "endstop_flag"
23 void endstop_isr(void) __interrupt(IE0_VECTOR);
24
25 #endif // ENDSTOP_H
```
Listing C.8: Endstop Driver Source

```
1 /* ENDSTOP ISR */
2 // Dominic Doty
3 // ECEN 5613
4
5
6 /* INCLUDES */7 #include "endstop .h"
8
9
10 /* GLOBALS */
11 volatile __bit endstop_flag = 0;
12
13 /* FUNCTION DEFINITIONS */
14 void endstop_configure(void)
15 {
16 ENDSTOP = 1;
17
18 IE0 = 0; // Clear int?
19 IT0 = 1; // Set to negative edge sensitive
20
21 PX0L; // Set priority
22 IPH0 &= PX0H;
```

```
23
24 EX0 = 1; // Enable int
25
26 // Set the endtop flag if the endstop is already triggered
27 if(ENDSTOP == 0)
28 {
29 endstop_flag = 1;
30 }
31 }
32
33 void endstop_isr(void) __interrupt(IE0_VECTOR)
34 {
35 endstop_flag = 1;
36 TR0 = 0;
37 }
```
Listing C.9: SPI Driver Header

```
1 /* SPI INTERFACE CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 #ifndef SPI_H
6 #define SPI_H
7
8 /* INCLUDES */
9 #include <stdint.h>
10 #include <stdio.h>
11 #include "mcs51/at89c51ed2 .h"
12 #include "pin_map.h"
13
14 /* DEFINES */
15
16
17 /* TYPEDEFS */
18 typedef enum{
19 spi\_ss\_enable = 0,
20 spi_ss_disable = 0b00100000
21 }Spi_SS_t;
22
23 typedef enum{
24 spi_mode_slave = 0,
25 spi_mode_master = 0b00010000
26 }spi_mode_t;
27
28 typedef enum{
29 spi_cpol_idle_high = 0b00001000,
30 spi_cpol_idle_low = 0
31 } } } } } } cpol_t;
32
33 typedef enum{
34 spi_cpha_sample_leave_idle = 0,
35 spi_cpha_sample_return_idle = 0b00000100
36 }spi_cpha_t;
37
38 typedef enum{
39 spi_baud_div2 = 0,
40 spi_baud_div4 = 1,
41 spi_baud_div8 = 2,
42 spi_baud_div16 = 3,
43 spi_baud_div32 = 0b10000000, // Weird because
                  config bits are
44 spi_baud_div64 = 0b10000001, // separated in the
                  SPCON register
45 spi_baud_div128 = 0b10000011
46 }spi_baud_div_t;
47
48 /* GLOBALS */
```

```
49
50
51 /* PROTOTYPES */
52 // Set up the SPI hardware
53 void spi_configure(
54 spi_ss_t ss_mode,
55 spi_mode_t mode,
56 spi_cpol_t cpol,
57 spi_cpha_t cpha,
58 spi_baud_div_t div);
59
60 // Perform a SPI transmission (and receive).
61 uint8_t spi_exchange(uint8_t tx);
62
63 #endif // SPI_H
```

```
Listing C.10: SPI Driver Source
```

```
1 /* SPI INTERFACE CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 /* INCLUDES */
6 #include " spi_driver .h"
7
8
9
10 /* FUNCTION DEFINITIONS */
11
12 void spi_configure(
13 spi_ss_t ss_mode,
14 spi_mode_t mode,
15 spi_cpol_t cpol,
16 spi_cpha_t cpha,
17 spi_baud_div_t div)
18 {
19 // disable spi (just in case)
20 SPCON &= ~SPEN;
21
22 // set gpio to high for MOSI MISO SCK
23 SPI_MOSI = 1;
24 SPI_MISO = 1;
25 SPI_SCK = 1;
26
27 // config SPCON baud, mode, cpol, cpha
28 SPCON = ss_mode | mode | cpol | cpha | div;
29
30 // enable
31 SPCON |= SPEN;
32 }
33
34 uint8_t spi_exchange(uint8_t tx)
```

```
35 {
36 SPDAT = tx; \frac{1}{36} SPDAT = tx;
37 while(!(SPSTA & SPIF)); // Wait for TX/RX complete flag
38
39 // Idle for a bit to prevent super fast back to back
           transmissions
40 for(uint8_t i = 0; i < 150; i++)
41 {
42 __asm NOP __endasm;
43 }
44
45 return SPDAT; \frac{1}{2} // Read RX data
46 }
```
Listing C.11: Capacitive Touch Driver Header

```
1 /* CAPACITIVE TOUCH INTERFACE CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 #ifndef CAPTOUCH_H
6 #define CAPTOUCH_H
7
8 /* INCLUDES */
9 #include <stdint.h>
10 #include <stdio.h>
11 #include "mcs51/at89c51ed2 .h"
12 #include "pin_map.h"
13 #include " spi_driver .h"
14 #include "delay .h"
15
16 /* DEFINES */
17 #define LONG_TOUCH_CODE 0x80
18 #define LONG_TOUCH_MULTIPLIER 30
19
20 /* TYPEDEFS */
21 typedef enum{
22 PLAY = 6,
23 STOP = 0,
24 MODE = 5,
25 SQ_UL = 7,
26 SQ_UR = 10,
27 SQ_LL = 8,
28 SQ_LR = 9,
29 UP = 2,
30 DOWN = 3,
31 LEFT = 1,
32 RIGHT = 4,
33 PLAY_LONG = PLAY + LONG_TOUCH_CODE,
34 STOP_LONG = STOP + LONG_TOUCH_CODE,
35 MODE_LONG = MODE + LONG_TOUCH_CODE,
36 SQ_UL_LONG = SQ_UL + LONG_TOUCH_CODE,
37 SQ_UR_LONG = SQ_UR + LONG_TOUCH_CODE,
38 SQ_LL_LONG = SQ_LL + LONG_TOUCH_CODE,
39 SQ_LR_LONG = SQ_LR + LONG_TOUCH_CODE,
40 UP_LONG = UP + LONG_TOUCH_CODE,
41 DOWN_LONG = DOWN + LONG_TOUCH_CODE,
42 LEFT_LONG = LEFT + LONG_TOUCH_CODE,
43 RIGHT_LONG = RIGHT + LONG_TOUCH_CODE,
14 NO_KEY = 0xff
45 }button_t;
46
47 /* GLOBALS */
48
49
50 /* PROTOTYPES */
```

```
51
52 // Configure the captouch IC AT42QT1110, verify status is good
53 void captouch_configure(void);
54
55 // Get the status of all buttons. If there is a failure this will
       return 0
56 button_t captouch_poll_buttons(void);
57
58 #endif // CAPTOUCH_H
```


```
1 /* CAPACITIVE TOUCH INTERFACE CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 /* INCLUDES */
6 #include "captouch_driver .h"
7
8
9 /* DEFINES */
10 #define CAPTOUCH_FIRST_KEY_REPT 0xC0
11 #define CAPTOUCH_ALL_KEYS_REPT 0xC1
12 #define CAPTOUCH_STATUS_REPT 0xC2
13 #define CAPTOUCH_QUICKSPI_ADDR 0x91
14 #define CAPTOUCH_QUICKSPI_DATA 0x04
15 #define CAPTOUCH_DIS_QUICKSPI 0x36
16 #define CAPTOUCH_CALIBRATE_ALL 0x03
17 #define CAPTOUCH_RESET 0x04
18 #define CAPTOUCH_IDLE 0x55
19 #define CAPTOUCH_STATUS_GOOD 0x80
20 #define CAPTOUCH_STATUS_MASK 0xF5
21 #define CAPTOUCH_MODE_SET 0x90
22 #define CAPTOUCH_MODE_GET 0xD0
23 #define CAPTOUCH_MODE 0xF0
24
25
26 /* TYPEDEFS */
27
28
29
30 /* FUNCTION DEFINITIONS */
31 void captouch_configure(void)
32 {
33 CS_CAPT = 1; // Set CS in case it started low
34 CS_CAPT = 0; // Assert CS
35
36 uint8_t rx;
37
38 // Check mode
39 spi_exchange(CAPTOUCH_MODE_GET);
40 rx = spi_exchange(0x00);
```

```
41
42 while(rx != CAPTOUCH_MODE)
43 {
44 rx = spi_exchange(CAPTOUCH_MODE_SET);
45 if(rx == CAPTOUCH_IDLE)
46 {
47 spi_exchange(CAPTOUCH_MODE);
48 spi_exchange(CAPTOUCH_MODE_GET);
49 rx = spi_exchange(0x00);
50 }
51 else
52 {
53 spi_exchange(0x00);
54 }
55 }
56
57 spi_exchange(CAPTOUCH_CALIBRATE_ALL);
58
59 CS_CAPT = 1; // Deassert CS
60 }
61
62 button_t captouch_poll_buttons(void)
63 {
64 uint8_t rx;
65 button_t button;
66
67 CS_CAPT = 0; // Assert CS
68
69 // Send nulls till the chip is idle (should be idle first tx)
70 do
71 {
72 rx = spi_exchange(0x00);
73 Example 18 Your Set 10 Fear 1 Point 2 Fear 1 Point 2
74
75 spi_exchange(CAPTOUCH_FIRST_KEY_REPT); // command/status
76 rx = (spi_exchange(0x00));
77
78 CS_CAPT = 1; // Deassert CS
79
80 if(rx & 0x80)
81 {
82 // Key in detect
83 button = rx & 0x0F; // mask out the key number
                  only
84 }
85 else
86 {
87 button = NO_{-}KEY;
88 }
89
90 return button;
91 }
```
Listing C.13: ADC Driver Header

```
1 /* ADC INTERFACE CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 #ifndef ADC_H
6 #define ADC_H
7
8 /* INCLUDES */
9 #include <stdint.h>
10 #include <stdio.h>
11 #include "mcs51/at89c51ed2 .h"
12 #include "pin_map.h"
13 #include " spi_driver .h"
14
15 /* DEFINES */
16 #define ADC_8BIT 0x01 // set to 1 to only get MS 8
      bits, set to zero to get 10 bits
17
18 /* TYPEDEFS */
19
20 typedef enum{
21 adc_mode_single = 0x08,
22 adc_mode_differential = 0 \times 0023 }adc_mode_t;
24
25 // Also defines which channel is + input for differential mode
26 typedef enum{
27 adc_channel_0 = 0 \times 00,
28 adc_channel_1 = 0x4029 }adc_channel_t;
30
31 /* GLOBALS */
32
33
34 /* PROTOTYPES */
35 // Setup the ADC (clear the bus)
36 void adc_configure(void);
37
38 // Take an ADC reading in single or diff mode, select chan (or
      positive end)
39 // 8 bit or 10 bit mode is set by DEFINE in adc_driver
40 #if ADC_8BIT == 0 \times 0141 uint8_t adc_reading(adc_mode_t mode, adc_channel_t chan);
42 #else
43 uint16_t adc_reading(adc_mode_t mode, adc_channel_t chan);
44 #endif
45
46
47 #endif // ADC_H
```
Listing C.14: ADC Driver Source

```
1 /* ADC INTERFACE CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 /* INCLUDES */
6 #include "adc_driver .h"
7
8
9 /* DEFINES */
10 #define ADC_START_BIT 0x10
11 #define ADC_MSBF 0x02
12
13 /* FUNCTION DEFINITIONS */
14
15 void adc_configure(void)
16 {
17 //if device was powered up with cs low, it must be brought
            high and then low to reinint
18 CS_ADC = 1;
19 CS_ADC = 0;20 CS_ADC = 1;
21 }
22
23 #if ADC_8BIT == 0 \times 0124 uint8_t adc_reading(adc_mode_t mode, adc_channel_t chan)
25 #else
26 uint16_t adc_reading(adc_mode_t mode, adc_channel_t chan)
27 #endif
28 {
29 // clocked out on falling edges and latched on rising edges
30 // clock idles low
31 // CPOL, CPHA = 0,0 or 1,1?
32
33 uint16_t result;
34
35 // CS goes low
36 CS_ADC = 0;
37
38 #if ADC_8BIT == 0x01
39 // 8 Bit Mode:
40 // TX: 0 0 0 SB MODE CHAN MSBF 0
41 // RX: DC
42 spi_exchange(ADC_START_BIT | mode | chan | ADC_MSBF);
43
44 // TX: 0x00
45 // RX: MS 8 bits
46 result = spi_exchange(0x00);
47
48 #else
49 uint8_t result_8;
```

```
50
51 // 10 Bit Mode:
52 // TX: 0 SB MODE CHAN MSBF 0 0 0
53 // RX: DC + MS 2 bits (in 0 and 1)
54 result_8 = spi_exchange((ADC_START_BIT | mode | chan | msbf)
           <<2);
55
56 // TX: 0x00
57 // RX: LS 8 bits
58 result = spi_exchange(0x00);
59
60 // Combine MSB's with the LSB's
61 result = ((result - 8 \& 0x03) << 8);62
63 #endif
64
65 // CS goes high
66 CS_ADC = 1;
67
68 return result;
69 }
```
Listing C.15: Thermistor Driver Header

```
1 /* THERMISTOR CONVERSION LOOKUP CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 #ifndef THERMISTOR_H
6 #define THERMISTOR_H
7
8 /* INCLUDES */
9 #include <stdint.h>
10 #include <stdio.h>
11 #include "mcs51/at89c51ed2 .h"
12 #include "pin_map.h"
13
14 /* DEFINES */
15
16
17 /* TYPEDEFS */
18
19
20 /* GLOBALS */
21
22
23 /* PROTOTYPES */
24
25 // Takes a raw ADC reading and converts it to a temperature in
       Fahrenheit
26 uint8_t thermistor_convert(uint8_t adc_reading);
27
28
29 #endif // THERMISTOR_H
```
Listing C.16: Thermistor Driver Source

```
1 /* THERMISTOR CONVERSION LOOKUP CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 /* INCLUDES */
6 #include " thermistor .h"
7
8
9 /* FUNCTION DEFINITIONS */
10
11 uint8_t thermistor_convert(uint8_t adc_reading)
12 {
13 // Using simple linear conversion for now, maybe tune this
              later if not accurate
14 uint8_t temperature = 274 - ( ( ((uint16_t)adc_reading) * 31)
               /32);
15 return temperature;
```
16 }

Listing C.17: Debug Printing Header

```
1 /* DEBUG PRINTING CODE */
2 // Dominic Doty
3 // ECEN 5613
4
5 #ifndef DEBUG_H
6 #define DEBUG_H
7
8 #ifdef DEBUG_PRINT
9 #include " serial .h"
10
11 #define debug_print(fmt, ...) printf_tiny(fmt, __VA_ARGS__)
12 #else
13 #define debug_print(fmt, ...) // Nothing
14 #endif
15
16 #ifdef DEBUG_ASM_CHAR
17 #define HASH_LIT #
18 #define HASH() HASH_LIT
19
20 #define asm_put(CHAR, LABEL)
21 LABEL:
22 jnb \_TI , LABEL \setminus23 clr \Box TI
24 mov _SBUF, HASH()CHAR
25 #else
26 #define asm_put(CHAR, LABEL) // Nothing
27 #endif
28
29 #endif // DEBUG_H
```
Listing C.18: Delay Functions Header

```
1 /* ====== BASIC DELAY ====== */
2 // Dominic Doty
3 // ECEN 5613
4
5 #ifndef DELAY_H
6 #define DELAY_H
7
8 /* INCLUDES */
9 #include <stdint.h>
10 #include <stdio.h>
11
12 /* DEFINES */
13
14 /* TYPEDEFS */
15
16 /* GLOBALS */
17
18 /* PROTOTYPES */
19 void seventyms_delay(void);
20
21 #endif // DELAY_H
```
Listing C.19: Delay Functions Source

```
1 /* ====== BASIC DELAY ====== */
2 // Dominic Doty
3 // ECEN 5613
4
5
6 /* ====== HEADER ====== */7 #include "delay .h"
8
9
10
11 /* ====== FUNCTION DEFINITIONS ====== */
12 void seventyms_delay(void)
13 {
14 for(uint8_t i = 0; i < 255; i++)
15 {
16 for(uint8_t j = 0; j < 255; j++)
17 		 {
18 2219 NOP;
20 __endasm;
21 }
22 }
23 }
```
D

L.

PART DATASHEETS

d.1 relay datasheet

Power PCB Relay RZF

- \blacksquare 1 pole, 16A, 1 form A (NO)
- n Coil power 530mW
- Reinforced insulation (EN 61810, 60335, 60730)
- \blacksquare Ambient temperature up to 85°C
- \blacksquare Quick connect terminals for load
- Low mounted height of 17.9mm (27.6mm with quick connects)
- WG version with material in acordance with IEC 60335-1

Typical applications Microwave ovens, water heaters, ovens, industrial equipment.

Approvals
VDE 40046175, UL E214025, CQC 17002175064

Technical data of app

Contact ratings 16A, 250VAC, resistive, 23°C, 100x10³ ops.
16A, 250VAC, resistive, 85°C, 100x10³ ops. Mechanical endurance

Electrical endurance

 \mathbf{R} us ω pe ∞

Coil Operating Range

voltage [U/Urtd]

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Catalog and product specification according to IEC 61810-1 and to be used only together with the 'Definitions' section.

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1 Catalog product data, 'Definitions' section, application notes and all specifications are subject to change.

Power PCB Relay RZF (Continued)

Insulation Data

Dimensions

- All terminal dimensions valid for the untinned terminal
- For the tin-plating of the pins add +0,1mm for the width, thickness or diameter.

Terminal assignment
Bottom view on solder pins

grid pattern: 2.50 to 2,54
hole diameter: ø1.3 +0,1
Bottom view on solder pins
dimensions in mm

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Power PCB Relay RZF (Continued)

Note: May be followed by up to five additional characters for manufacturer internal identification.

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Power PCB Relay RZF (Continued)

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d.2 adc datasheet

2.7V Dual Channel 10-Bit A/D Converter with SPI Serial Interface

Description

• 10-bit resolution

Features

- ±1 LSB maximum DNL
- ±1 LSB maximum INL • Analog inputs programmable as single-ended or pseudo-differential pairs
- On-chip sample and hold
- SPI serial interface (modes 0,0 and 1,1)
- Single supply operation: 2.7V 5.5V
- 200 ksps max sampling rate at $V_{DD} = 5V$
- 75 ksps max sampling rate at V_{DD} = 2.7V
-
- Low power CMOS technology: 5 nA typical standby current, 2 µA maximum - 550 µA maximum active current at 5V
- Industrial temperature range: -40°C to +85°C
- 8-pin MSOP, PDIP, SOIC and TSSOP packages

Applications

- Sensor Interface
- Process Control
- Data Acquisition
- Battery Operated Systems

Functional Block Diagram

The MCP3002 is a successive approximation 10-bit analog-to-digital (A/D) converter with on-board sample and hold circuitry. The MCP3002 is programmable to provide a single

pseudo-differential input pair or dual single-ended inputs. Differential Nonlinearity (DNL) and Integral Nonlinearity (INL) are both specified at ±1 LSB. Com-munication with the device is done using a simple serial interface compatible with the SPI protocol. The device is capable of conversion rates of up to 200 ksps at 5V and 75 ksps at 2.7V.

The MCP3002 operates over a broad voltage range, 2.7V to 5.5V. Low-current design permits operation with a typical standby current of 5 nA and a typical active current of 375 µA.

The MCP3002 is offered in 8-pin MSOP, PDIP, TSSOP and 150 mil SOIC packages.

Package Types

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1.0 ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings †

VDD ..7.0V All Inputs and Outputs w.r.t. VSS -0.6V to VDD + 0.6V Storage Temperature.....................................-65°C to +150°C Ambient temperature with power applied.......-65°C to +150°C ESD Protection On All Pins (HBM) 4 kV

ELECTRICAL CHARACTERISTICS

Note 1: This parameter is established by characterization and not 100% tested.
2: The sample cap will eventually lose charge, especially at elevated temperatures, therefore f_{CLK} ≥10 kHz for
temperatures at or above 70

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T Motice: Stresses above those listed under "Absoluter"
Maximum Ratings" may cause permanent damage to the
device. This is a stress rating only and functional operation of
the device at those or any other conditions above

Note 1: This parameter is established by characterization and not 100% tested.
21 The sample cap will eventually lose charge, especially at elevated temperatures, therefore f_{CLK} ≥10 kHz for
temperatures at or above 70°C

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TEMPERATURE CHARACTERISTICS

FIGURE 1-1: Serial Timing.

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2.0 TYPICAL PERFORMANCE CHARACTERISTICS

Note: The graphs provided following this note are a statistical summary based on a limited number of samples and are provided for informational purposes only. The performance characteristics listed herein are not tested or guaranteed. In some graphs, the data presented may be outside the specified operating range (e.g., outside specified power supply range) and therefore outside the warranted range.

vs. Sample Rate.

FIGURE 2-2: Integral Nonlinearity (INL) vs. Code.

FIGURE 2-4: Integral Nonlinearity (INL)
vs. Sample Rate (V_{DD} = 2.7V).

FIGURE 2-5: Integral Nonlinearity (INL) vs. Code (V_{DD} = 2.7V).

FIGURE 2-6: Integral Nonlinearity (INL)
vs. Temperature (V_{DD} = 2.7V).

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vs. $V_{DD.}$

(DNL) vs. Sample Rate.

MCP3002

Differential Nonlinearity **FIGURE 2-10:**
(DNL) vs. V_{DD.}

(DNL) vs. Sample Rate (V_{DD} = 2.7V).

FIGURE 2-15: Gain Error vs. Temperature.

-50 -25 0 25 50 75 100 Temperature (°C)

fSAMPLE = 75 ksps

Note: Unless otherwise indicated, $V_{DD} = 5V$, $f_{SAMPLE} = 200$ ksps, $f_{CLK} = 16* f_{SAMPLE}$, $T_A = +25°C$.

 $-0.4 + 50$ **-0.3 -0.2 -0.1 0.0 0.1 -50 -25 0 25 50 75 100 Temperature (°C) Negative DNL**

V_{DD} = 2.7V
f_{SAMPLE} = 75 ksps

Positive DNL

FIGURE 2-16: Differential Nonlinearity (DNL) vs. Temperature (V_{DD} = 2.7V).

FIGURE 2-17: Offset Error vs. V_{DD}.

FIGURE 2-18: Offset Error vs. Temperature.

-0.5 -0.4 -0.3 -0.2 -0.1

VDD = 5V fSAMPLE = 200 ksps

Gain Error (LSB)

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(THD) vs. Input Frequency.

MCP3002

Distortion (SINAD) vs. Input Frequency.

70	$V_{nn} = 5V$							
60	f_{SAMPLE} = 200 ksps							
SINAD (dB) 3 40 50 60 3 40 60								
20								
10			$V_{DD} = 2.7V$					
0			$f_{\text{SAMPL F}} = 75$ ksps					
-40	-35	-30		-20 -25	-15	-10	-5	

FIGURE 2-23: Signal-to-Noise and Distortion (SINAD) vs. Signal Level.

FIGURE 2-30: I_{DD} vs. Temperature.

FIGURE 2-27: Frequency Spectrum of
1 kHz input (Representative Part, V_{DD} = 2.7V).

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Note: Unless otherwise indicated, $V_{DD} = 5V$, $f_{SAMPLE} = 200$ ksps, $f_{CLK} = 16$ ^{*} f_{SAMPLE} , $T_A = +25$ °C.

FIGURE 2-31: I_{DDS} vs. V_{DD}.

FIGURE 2-33: Analog Input leakage current vs. Temperature.

3.0 PIN DESCRIPTIONS

The descriptions of the pins are listed in Table 3-1. Additional descriptions of the device pins follows.

TABLE 3-1: PIN FUNCTION TABLE

3.1 Analog Inputs (CH0/CH1)

Analog inputs for channels 0 and 1 respectively. These channels can programmed to be used as two indepen-dent channels in Single-Ended mode or as a single pseudo-differential input where one channel is IN+ and one channel is IN-. See **Section 5.0 "Serial Communications"** for information on programming the channel configuration.

3.2 Chip Select/Shutdown (CS/SHDN)

The CS/SHDN pin is used to initiate communication with the device when pulled low and will end a conver-
sion and put the device in low power standby when
pulled high. The CS/SHDN pin must be pulled high
between conversions.

3.3 Serial Clock (CLK)

The SPI clock pin is used to initiate a conversion and to clock out each bit of the conversion as it takes place. See **Section 6.2 "Maintaining Minimum Clock Speed"** for constraints on clock speed.

3.4 Serial Data Input (D_{IN})

The SPI port serial data input pin is used to clock in input channel configuration data.

3.5 **Serial Data Output (DOUT)**

The SPI serial data output pin is used to shift out the results of the A/D conversion. Data will always change on the falling edge of each clock as the conversion takes place.

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4.0 DEVICE OPERATION

The MCP3002 A/D converter employs a conventional SAR architecture. With this architecture, a sample is acquired on an internal sample/hold capacitor for 1.5 clock cycles starting on the second rising edge of the serial clock after the start bit has been received. Following this sample time, the input switch of the converter opens and the device uses the collected charge on the internal sample and hold capacitor to produce a serial 10-bit digital output code.

Conversion rates of 200 ksps are possible on the MCP3002. See **Section 6.2 "Maintaining Minimum Clock Speed"** for information on minimum clock rates. Communication with the device is done using a 3-wire SPI-compatible interface

4.1 Analog Inputs

The MCP3002 device offers the choice of using the analog input channels configured as two single-ended
inputs that are referenced to V_{SS} or a single pseudo-
differential input. The configuration setup is done as part of the serial command before each conversion begins. When used in the pseudo-differential mode, CH0 and CH1 are programmed as the IN+ and IN- inputs as part of the command string transmitted to the device. The IN+ input can range from IN- to the reference voltage,
V_{DD}. The IN- input is limited to ±100 mV from the V_{SS} rail. The IN- input can be used to cancel small signal common-mode noise which is present on both the IN+ non-mode noise which is present on both the IN+ and IN- inputs.

For the A/D converter to meet specification, the charge holding capacitor (C_{SAMPLE}) must be given enough
time to acquire a 10-bit accurate voltage level during the 1.5 clock cycle sampling period. The analog input
model is shown in Figure 4-1.

In this diagram, it is shown that the source impedance (R_S) adds to the internal sampling switch (R_{SS}) imped-
ance, directly affecting the time that is required to charge the capacitor, C_{SAMPLE}. Consequently, larger
source impedances increase the offset, gain, and integral linearity errors of the conversion.

Ideally, the impedance of the signal source should be near zero. This is achievable with an operational amp lifer such as the MCP601 which has a closed loop output impedance of tens of ohms. The adverse affects of higher source impedances are shown in Figure 4-2.

When operating in the pseudo-differential mode, if the voltage level of IN+ is equal to or less than IN-, the resultant code will be 000h. If the voltage at IN+ is equal
to or greater than {[V_{DD} + (IN-)] - 1 LSB}, then the output code will be 3FFh. If the voltage level at IN- is more
than 1 LSB below V_{SS}, then the voltage level at the IN+ input will have to go below V_{SS} to see the 000h output
code. Conversely, if IN- is more than 1 LSB above
V_{SS}, then the 3FFh code will not be seen unless the

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MCP3002

 $IN+$ input level goes above V_{DD} level. If the voltage at IN+ is equal to or greater than ${[V_{DD} + (IN-)]} - 1$ LSB},
then the output code will be 3FFh.

4.2 Digital Output Code

The digital output code produced by an A/D Converter
is a function of the input signal and the reference
voltage. For the MCP3002, V_{DD} is used as the reference voltage.

As the V_{DD} level is reduced, the LSB size is reduced accordingly. The theoretical digital output code produced by the A/D Converter is shown below.

Digital Output Code = $\frac{1024 \times V_{IN}}{V_{DD}}$ Where: *VIN* = analog input voltage V_{DD} = supply voltage

FIGURE 4-2: Maximum Clock Frequency vs. Input resistance (RS) to maintain less than a 0.1 LSB deviation in INL from nominal conditions.

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5.0 SERIAL COMMUNICATIONS

5.1 Overview

Communication with the MCP3002 is done using a standard SPI-compatible serial interface. Initiating communication with the device is done by bringing the CS line low. See Figure 5-1. If the device was powered
up with the CS pin low, it must be brought high and back low to initiate communication. The first clock
received with CS low and D_{IN} high will constitute a start
bit. The SGL/DIFF bit and the ODD/SIGN bit follow the start bit and are used to select the input channel config-
uration. The SGL/DIFF is used to select Single-Ended
or Pseudo-Differential mode. The ODD/SIGN bit selects which channel is used in Single-Ended mode, and is used to determine polarity in Pseudo-Differential mode. Following the ODD/SIGN bit, the MSBF bit is transmitted to and is used to enable the LSB first format for the device. If the MSBF bit is high, then the data will come from the device in MSB first format and any fur-ther clocks with CS low, will cause the device to output zeros. If the MSBF bit is low, then the device will output
the converted word LSB first *after* the word has been
transmitted in the MSB first format. Table 5-1 shows the configuration bits for the MCP3002. The device will begin to sample the analog input on the second rising edge of the clock, after the start bit has been received. The sample period will end on the falling edge of the third clock following the start bit.

On the falling edge of the clock for the MSBF bit, the device will output a low null bit. The next sequential 10 clocks will output the result of the conversion with MSB first as shown in Figure 5-1. Data is always output from
the device on the falling edge of the clock. If all 10 data
bits have been transmitted and the device continues to
receive clocks while the $\overline{\text{CS}}$ is held low (bit is high), the device will output the conversion result LSB first as shown in Figure 5-2. If more clocks are pro-
vided to the device while CS is still low (after the LSB
first data has been transmitted), the device will clock out zeros indefinitely.

MCP3002

If necessary, it is possible to bring $\overline{\text{CS}}$ low and clock in leading zeros on the D_{IN} line before the start bit. This is
often done when dealing with microcontroller-based SPI ports that must send 8 bits at a time. Refer to
Section 6.1 "Using the MCP3002 with Microcon-
troller (MCU) SPI Ports" for more details on using the
MCP3002 devices with hardware SPI ports.

If it is desired, the $\overline{\text{CS}}$ can be raised to end the conversion period at any time during the transmission. Faster conversion rates can be obtained by using this technique if not all the bits are captured before starting a new cycle. Some system designers use this method by capturing only the highest-order 8 bits and 'throwing away' the lower 2 bits.

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6.0 APPLICATIONS INFORMATION

6.1 Using the MCP3002 with Microcontroller (MCU) SPI Ports

With most microcontroller SPI ports, it is required to send groups of eight bits. It is also required that the microcontroller SPI port be configured to clock out data on the falling edge of clock and latch data in on the rising
edge. Depending on how communication routines are
used, it is very possible that the number of clocks
required for communication will not be a multiple of
eight. usually done by sending 'leading zeros' before the start bit, which are ignored by the device.

As an example, Figure 6-1 and Figure 6-2 show how the MCP3002 can be interfaced to a MCU with a hardware SPI port.

Figure 6-1 depicts the operation shown in SPI Mode 0,0, which requires that the SCLK from the MCU idles in the 'low' state, while Figure 6-2 shows the similar case of
SPI Mode 1,1 where the clock idles in the 'high' state.

As shown in Figure 6-1, the first byte transmitted to the A/D Converter contains one leading zero before the start bit. Arranging the leading zero this way produces the output 10 bits to fall in positions easily manipulated by the MCU. When the first 8 bits are transmitted to the device, the MSB data bit is clocked out of the A/D converter on the falling edge of clock number 6. After the second eight clocks have been sent to the device, the receive register will contain the lowest-order eight bits of the conversion results. Easier manipulation of the converted data can be obtained by using this method.

high).

6.2 Maintaining Minimum Clock Speed

When the MCP3002 initiates the sample period, charge is stored on the sample capacitor. When the sample period is complete, the device converts one bit for each clock that is received. It is important for the user to note that a slow clock rate will allow charge to bleed off the sample cap while the conversion is taking place. At 85°C (worst case condition), the part will maintain
proper charge on the sample cap for 700 µs at
 $V_{DD} = 2.7V$ and 1.5 ms at $V_{DD} = 5V$. This means that at
 $V_{DD} = 2.7V$, the time it takes to transmit the 1.5 clocks
for th conversion must not exceed 700 µs. Failure to meet this criteria may induce linearity errors into the conversion outside the rated specifications.

6.3 Buffering/Filtering the Analog Inputs

If the signal source for the A/D Converter is not a low impedance source, it will have to be buffered or inaccurate conversion results may occur. It is also recommended that a filter be used to eliminate any signals that may be aliased back in to the conversion results. This is illustrated in Figure 6-3 below where an
op amp is used to drive, filter, and gain the analog input of the MCP3002. This amplifier provides a low impedance output for the converter input and a low-pass filter, which eliminates unwanted high-frequency noise.

Low-pass (anti-aliasing) filters can be designed using Microchip's interactive FilterLab**®** software. FilterLab will calculate capacitor and resistors values, as well as, determine the number of poles that are required for the application. For more information on filtering signals, see the application note AN699 *"Anti-Aliasing Analog Filters for Data Acquisition Systems."*

FIGURE 6-3: Typical Anti-Aliasing Filter Circuit (2 pole Active Filter).

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6.4 Layout Considerations

When laying out a printed circuit board for use with
analog components, care should be taken to reduce
noise wherever possible. A bypass capacitor should
always be used with this device and should be placed
as close as pos capacitor value of 1 µF is recommended.

Digital and analog traces should be separated as much
as possible on the board and no traces should run
underneath the device or the bypass capacitor. Extra
precautions should be taken to keep traces with high-
frequency s

Use of an analog ground plane is recommended in order to keep the ground potential the same for all
devices on the board. Providing V_{DD} connections to
devices in a "star" configuration can also reduce noise
by eliminating current return paths and associated
errors. Se (DS00688).

FIGURE 6-4: V_{DD} traces arranged in a
'Star' configuration in order to reduce errors
caused by current return paths.

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MCP3002

7.1 Package Marking Information

7.0 PACKAGING INFORMATION

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Package Marking Information (Continued)

8-Lead TSSOP (4.4 mm) Example

8-Lead Plastic Micro Small Outline Package (MS) [MSOP]

Notes:

1. Pin 1 visual index feature may vary, but must be located within the hatched area.
2. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.15 mm per side.
3. Dimensio

Microchip Technology Drawing C04-111B

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RECOMMENDED LAND PATTERN

Notes:

www.
1. Dimensioning and tolerancing per ASME Y14.5M
BSC: Basic Dimension. Theoretically exact value shown without tolerances.

Microchip Technology Drawing No. C04-2111A

8-Lead Plastic Dual In-Line (P) - 300 mil Body [PDIP]

Notes:
2. § Significant Characteristic.
2. § Significant Characteristic.
2. § Significant Characteristic.
4. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed .010"

Microchip Technolo Microchip Technology Drawing C04-018B

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Microchip Technology Drawing No. C04-057C Sheet 1 of 2

8-Lead Plastic Small Outline (SN) - Narrow, 3.90 mm Body [SOIC]

Note: For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging

Notes:

Notes:

2. Since I visual index feature may vary, but must be located within the hatched area.

2. Since I visual index feature may vary, but must be located within the hatched area.

2. Since I visual index cosed 0.15mm p

Microchip Technology Drawing No. C04-057C Sheet 2 of 2

DS21294E-page 26 2000-2011 Microchip Technology Inc.

8-Lead Plastic Small Outline (SN) - Narrow, 3.90 mm Body [SOIC]

RECOMMENDED LAND PATTERN

Notes:

notes.
1. Dimensioning and tolerancing per ASME Y14.5M
BSC: Basic Dimension. Theoretically exact value shown without tolerances.

Microchip Technology Drawing No. C04-2057A

8-Lead Plastic Thin Shrink Small Outline (ST) - 4.4 mm Body [TSSOP]

Notes:

2. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.15 mm per side.

2. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusi

7& - -

1.00 RE

Length | L | 0.45 | 0.60 | 0.75

Angle ϕ 0° 8°

4!! @

B#&) @ -

tprint 1.00

Molded Package

Foot

Foo

Foot

Lead Thickn

Lead Width

Microchip Technolo Microchip Technology Drawing C04-086B

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8-Lead Plastic Thin Shrink Small Outline (ST) - 4.4 mm Body [TSSOP]

Note: For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging

RECOMMENDED LAND PATTERN

Notes:

ועטופא.
1. Dimensioning and tolerancing per ASME Y14.5M
BSC: Basic Dimension. Theoretically exact value shown without tolerances.

Microchip Technology Drawing No. C04-2086A

APPENDIX A: REVISION HISTORY

Revision E (November 2011)

Updated **Product Identification System** Corrected MSOP marking drawings. Updated Package Specification Drawings with new additions.

Revision D (October 2008) Updates to packaging outline drawings.

Revision C (January 2007)

Updates to packaging outline drawings.

Revision B (August 2001) Undocumented changes.

Revision A (February 2000)

Initial release of this document.

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PRODUCT IDENTIFICATION SYSTEM

To order or obtain information, e.g., on pricing or delivery, refer to the factory or the listed sales office.

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MCP3002

NOTES:

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Note the following details of the code protection feature on Microchip devices:

- Microchip products meet the specification contained in their particular Microchip Data Sheet.
- Microchip believes that its family of products is one of the most secure families of its kind on the market today, when used in the intended manner and under normal conditions.
- There are dishonest and possibly illegal methods used to breach the code protection feature. All of these methods, to our knowledge, require using the Microchip products in a manner outside the operating specifications contained in Microchip's Data
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Mindi, MiWi, MPASM, MPLAB Certified logo, MPLIB,
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d.3 capacitive touch ic datasheet

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1. Pinout and Schematic

1.1 Pinout Configuration

1.2 Pin Descriptions

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For component values in Figure 1-1, Figure 1-2 and Figure 1-3, check the following sections:

SNS10/DETECT6
SNS10/DETECT6
(0 (0 (0

9 $\frac{1}{\sqrt{2}}$

- Section 3.1 on page 9: Cs capacitors (Cs0 Cs10)
- Section 3.2 on page 9: Sample resistors (Rs0 Rs10)
- **Section 3.5 on page 10: Voltage levels**
- Section 3.3 on page 9: LED traces

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External Timing Control

2. Overview of the AT42QT1110

2.1 Introduction

The AT42QT1110 (QT1110) is a digital burst mode charge-transfer (QT™) capacitive sensor driver designed for any touch-key applications.

The keys can be constructed in different shapes and sizes. Refer to the *Touch Sensors Design Guide* and Application Note QTAN0002, *Secrets of a Successful QTouch Design*, for more information on construction and design methods (both downloadable from the Atmel website).

The device includes all signal processing functions necessary to provide stable sensing under a wide variety of changing conditions, and the outputs are fully debounced. Only a few external parts are required for operation.

The QT1110 modulates its bursts in a spread-spectrum fashion in order to suppress heavily the effects of external noise, and to suppress RF emissions.

2.2 Configurations

The QT1110 is designed as a versatile device, capable of various configurations. There are two basic configurations for the QT1110:

- **11-key QTouch. The device can sense up to 11 keys.**
- 7-key QTouch with individual outputs for each key. The device can sense up to 7 keys and drive the matching Detect outputs to a user-configurable PWM.

Both configurations allow for a choice of acquisition modes, thus providing a variety of possibilities that will satisfy most applications (see the following sections for more information).

Additionally, the SYNC line can be used as an external trigger input. Note that in 11-key mode the SYNC line replaces one key, thus allowing only 10 keys.

See Section 4.7 on page 18 for more information.

2.3 Guard Channel

The device has a guard channel option (available in all key modes), which allows one key to be configured as a guard channel to help prevent false detection. See Section 4.9 on page 20 for more information.

2.4 Self-test Functions

- The QT1110 has two types of self-test functions:
- **Internal Hardware tests check for hardware failures in the device internal memory.**
- **•** Functional checks confirm that the device is operating within expected parameters.

See Section 4.10 on page 20 for more information.

2.5 Moisture Tolerance

The presence of water (condensation, sweat, spilt water, and so on) on a sensor can alter the signal values measured and thereby affect the performance of any capacitive device. The moisture tolerance of QTouch devices can be improved by designing the hardware and fine-tuning the firmware following the recommendations in the application note Atmel *AVR3002: Moisture Tolerant QTouch Design* (www.atmel.com/Images/doc42017.pdf).

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3. Wiring and Parts

3.1 Cs Sample Capacitors

Cs0 – Cs10 are the charge sensing sample capacitors. Normally they are identical in nominal value. The optimal Cs values depend on the thickness of the panel and its dielectric constant. Thicker panels require larger values of Cs. Values can be in the range 2.2 nF (for faster operation) to 33 nF (for best sensitivity); typical values are 4.7 nF to 10 nF.

The value of Cs should be chosen so that a light touch on a key produces a reduction of ~20 to 30 in the key signal value (see Section 6.8 on page 27). The chosen Cs value should never be so large that the key signals exceed ~1000, as reported by the chip in the debug data.

The Cs capacitors must be X7R or PPS film type, for stability. For consistent sensitivity, they should have a 10 percent tolerance. Twenty percent tolerance may cause small differences in sensitivity from key to key and unit to unit. If a key is not used, the Cs capacitor may be omitted.

3.2 Rs Resistors

The series resistors Rs0 – Rs10 are inline with the electrode connections and should be used to limit electrostatic discharge (ESD) currents and to suppress radio frequency (RF) interference. Values should be approximately 2 k Ω to 20 k Ω each; a typical value is 4.7 k Ω .

Although these resistors may be omitted, the device may become susceptible to external noise or radio frequency interference (RFI). For details of how to select these resistors see the Application Note QTAN0002, *Secrets of a Successful QTouch Design*, downloadable from the Touch Technology area of the Atmel website, www.atmel.com.

3.3 LED Traces and Other Switching Signals

Digital switching signals near the sense lines can induce transients into the acquired signals, deteriorating the SNR performance of the device. Such signals should be routed away from the sensing traces and electrodes, or the design should be such that these lines are not switched during the course of signal acquisition (bursts).

LED terminals which are multiplexed or switched into a floating state, and which are within, or physically very near, a key (even if on another nearby PCB) should be bypassed to either Vss or Vdd with at least a 1 nF capacitor. This is to suppress capacitive coupling effects which can induce false signal shifts. The bypass capacitor does not need to be next to the LED, in fact it can be quite distant. The bypass capacitor is noncritical and can be of any type. LED terminals which are constantly connected to Vss or Vdd do not need further bypassing.

3.4 PCB Cleanliness

Modern no-clean flux is generally compatible with capacitive sensing circuits.

CAUTION: If a PCB is reworked to correct soldering faults relating to the QT1110, or to any associated traces or components, be sure that you fully understand the nature of the flux used during the rework process. Leakage currents from hygroscopic ionic residues can stop capacitive sensors from functioning. If you have any doubts, a thorough cleaning after rework may be the only safe option.

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It is assumed that a larger bypass capacitor (like1 µF) is somewhere else in the power circuit; for example, near the regulator.

3.5.2 Brownout Detection

The QT1110 includes a power supply monitoring circuit that detects if Vdd drops below a safe operating voltage. When this occurs, the device goes into a *Reset* state, where no acquisition or processing is carried out. The device remains in this state until Vdd returns to the specified voltage range.

Once a safe operating voltage is detected, the QT1110 behaves as per normal power-on/reset conditions; that is, any saved settings are restored from EEPROM, the internal self-tests are run and all channels are calibrated. The Brown-out detector threshold is 2.7 V ±10%.

3.6 MLF Package Restrictions

The central pad on the underside of the MLF chip should be connected to ground. Do not run any tracks underneath the body of the chip, only ground. Figure 3-1 shows examples of good and bad tracking.

Figure 3-1. Examples of Good and Bad Tracking

Example of GOOD tracking Example of BAD tracking

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4. Detailed Operations

4.1 Communications

4.1.1 Introduction

All communication with the device is carried out over the Serial Peripheral Interface (SPI). This is a synchronous serial data link that operates in full-duplex mode. The host communicates with the QT controller over the SPI using a master-slave relationship, with the QT1110 acting in slave mode.

4.1.2 SPI Operation

The SPI uses four logic signals:

- **Serial Clock (SCK)** output from the host.
- Master Output, Slave Input (MOSI) output from the host, input to the QT controller. Used by the host to send data to the QT controller
- Master Input, Slave Output (MISO) input to the host, output from the QT controller. Used by the QT device to send data to the host.
- Slave Select $($ \overline{SS} $)$ active low output from the host.

At each byte, the master pulls $\overline{\text{SS}}$ low and generates 8 clock pulses on SCK. With these 8 clock pulses, a byte of lata is transmitted from the master to the slave over MOSI, most significant bit (msb) first.

Simultaneously a byte of data is transmitted from the slave to the master over MISO, also most significant bit first. The slave reads the status of MOSI at the leading edge of each clock pulse, and the master reads the slave data from MISO at the trailing edge.

The QT1110 requires that the clock idles "high", meaning that the data on MOSI and MISO pins are set at the falling edges and sampled at the rising edges.

That is:

Clock polarity CPOL = 1 Clock phase CPHA = 1

The QT1110 SPI interface can operate at any SCK frequency up to 1.5 MHz.

In multibyte communications, the master must pause for a minimum delay of 150 µs between the completion of one byte exchange and the beginning of the next.

Note that the number of bytes to be transmitted depends on the initial command sent by the host. This sets the mode on the QT1110 so that the QT1110 knows how to respond to, or how to interpret, the following bytes. If there is a delay of >100 ms between bytes while the QT1110 is waiting for data, or waiting to send data, then the incomplete transmission is discarded and the device resets its SPI state machine. It will then interpret the next byte it receives as a fresh command.

When the QT1110 SPI interface is receiving a new command, it returns the *Idle* status code (0x55) on MISO during the first byte exchange to indicate to the master that it is in the correct state for receiving instructions.

4.1.3 CRC Bytes

If enabled, a CRC checking procedure is implemented on all communications between the SPI master and the QT1110. In this case, each command or report request sent by the master must have a byte appended containing the CRC checksum of the data sent. The QT1110 will not respond to commands until the CRC byte has been received and verified.

Sample C code showing the algorithm for calculating the CRC of the data can be found in Appendix A..

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4.1.5.1 Set Instructions

Set Instructions are 2-byte transmissions by the host that are used to send settings to individual locations in the device memory map.

At the first byte, the QT1110 returns 0x55 (*Idle*) to confirm that it will interpret the byte as a new command. At the second byte, the QT1110 returns the *Set* command it has just received.

For example, to set the *Positive Recalibration Delay* to 1920 ms, address 5 in the memory map is set to 12 (0x0C). This is done with the *Set* command for address 5 (command code 0x95), as shown in Figure 4-5.

Figure 4-5. Positive Recalibration Delay Set Instruction – CRC Disabled

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The host sends the appropriate *Get* command, followed by a *Null* byte. The QT1110 returns the contents of the addressed memory location.

Figure 4-7 shows the exchange for a report on the positive recalibration delay (assuming that the data byte is 0×0 C). With CRC Enabled, this exchange takes 4 bytes, with a command CRC transmitted by the host and a report CRC returned by the QT1110 (see Figure 4-8 on page 16).

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4.1.6 Quick SPI Mode

4.1.6.1 Introduction

In Quick SPI Mode, the QT1110 sends a 7-byte key report at each exchange. No host commands are required over SPI in this mode; the host clocks the data bytes out in sequence. Quick SPI mode is enabled by setting the *SPI_EN* bit in the Comms Options setup byte (see Section 7.5 on page 31).

4.1.6.2 Quick SPI Report

The 7 report bytes are in the format given in Table 4-1.

Table 4-1. Device Status Report Format

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where: Byte 0 is a counter that increments from 0 to 254 on successive exchanges to confirm that firmware is operating correctly. Bytes 1 – 3 indicate the detect status of channels $0 - 3$, $4 - 7$ and $8 - 10$ respectively (two bits per channel), as follows: \bullet 00 = Channel not in detect $01 =$ Channel in detect \bullet 10 = Not Allowed • 11 = Invalid Signal (Channel disabled) Bytes $4 - 6$ indicate the error status of channels $0 - 3$, $4 - 7$ and $8 - 10$ respectively (two bits per channel), as follows: $00 = No error$ \bullet 01 = Not allowed \bullet 10 = Error on channel \bullet 11 = Invalid signal (channel disabled) Successive byte exchanges in Quick SPI mode cycle through the 7 bytes of status information. If synchronization is lost, the host must either re-synchronize by identifying the incrementing counter byte (byte 0) or pausing communications for at least 100 ms so the QT1110 will reset its SPI state. **4.1.6.3 Commands in Quick SPI Mode** Only two host commands are recognized under Quick SPI mode. These are shown in Table 4-2. **Table 4-2. Host Commands in Quick SPI Mode Command Code Purpose** Store to EEPROM $0x0A$ Allows for "Quick SPI mode" to be stored as the default start-up mode Enable Full SPI $\Big|$ 0x36 Enables full SPI mode

CRC checking is not implemented in Quick SPI mode for host commands or return data.

4.1.6.4 Quick SPI Mode timing

In Quick SPI mode, the minimum time between byte exchanges is reduced to 50 µS.

If a pause in communications of 100 ms is detected during reading of the 7-byte report, the QT1110 resets the exchange, and on the next byte read it returns byte 0 of the report.

4.2 Reset

The QT1110 can be reset using one of two methods:

- **Hardware reset:** An external reset logic line can be used if desired, fed into the **RESET** pin. However, under most conditions it is acceptable to tie RESET to Vdd.
	- **Software reset:** A software reset can be forced using the "Reset" control command.

For both methods, the device will follow the same initialization sequence. If there any saved settings in the EEPROM, these are loaded into RAM. Otherwise the default settings are applied.

Note: The SPI interface becomes active after the QT1110 has completed its startup sequence, taking approximately 160 ms after power on/reset.

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4.3 Sleep Mode

The QT1110 can be put into a very low power sleep mode (typically < 2 µA). During sleep mode, no keys are measured and the DETECT outputs are all put into high impedance mode to minimize current consumption. The device remains in sleep mode until a falling edge is detected on either the SS pin or the CHANGE pin. When the QT1110 wakes from sleep mode, it continues to operate as it was before it was put into sleep mode. The QT1110 requires approximately 100 µs to wake from sleep mode and will not respond correctly to SPI communications until the wake-up procedure is complete. The low level on the SS or CHANGE pin that is used to wake the device must be maintained for 100 µs to ensure correct operation.

Note: If the device is set to sleep mode for an extended period, the host should initiate a recalibration immediately after waking the QT1110.

4.4 Calibration

The device can be forced to recalibrate the sensor keys at any time. This can be useful where, for example, a portable device is plugged into mains power, or during product development when settings are being tuned.

The QT1110 can also be configured to automatically recalibrate if it remains in detection for too long. This avoids keys becoming "stuck" after a prolonged period of uninterrupted detection. See Section 7.18 on page 38 for details.

4.5 CHANGE Pin

The CHANGE pin can be configured using the Comms Options setup byte (see Section 7.5 on page 31) to act in one of two modes:

- Data mode
	- The CHANGE pin is asserted (pulled low) when the detection status of a key changes from that last sent to the host; that is when a key-touch or key-release event occurs.
	- The CHANGE pin is pulled low when a key status changes and is only released when the "Send All keys" report is requested (0xC1), or the key status information bytes are read in Quick SPI mode (see 7.5 on page 31).
- **•** Touch mode
	- The CHANGE pin is pulled low when one or more keys are in detect. The CHANGE pin remains low as long as there is a key in detect, regardless of communications.
	- The CHANGE pin is released when there are no keys in detect. No host communications are required to release the CHANGE pin.

4.6 Stand-alone Mode

The QT1110 can operate in a stand-alone mode without the use of the SPI interface. The settings are loaded from EEPROM and the device operates in 7-key mode using the Detect outputs.

4.7 Key Modes

4.7.1 11-key Mode

In 11-key mode, the device can sense up to 11 keys. Alternatively, one key can be replaced by the SYNC line as an external trigger input (see Section 4.8.2 on page 19).

11-key mode is configured by setting the *MODE* bit in the Device Mode setup byte (see Section 7.4 on page 30). Key acquisition can be triggered in one of two ways: using the internal clock to trigger acquisition either at a fixed repetition period or in a continuous "free run" mode (see Section 4.8.1), or using the SYNC pin to provide an external trigger (see Section 4.8.2 on page 19),

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4.7.2 7-key Mode

In 7-key mode, the detect outputs DETECT0 to DETECT6 become active on pins 22 - 27 and 30. These outputs provide configurable PWM signals that indicate when each of the keys is touched.

7-key mode is configured by clearing the *MODE* bit in the Device Mode setup byte (see Section 7.4 on page 30).

Each DETECT output can be individually configured to output a PWM signal while the matching key is in detect or out of detect. This signal can be one of nine levels, ranging from low (PWM = 0%) to high (PWM = 100%). This allows for the use of an indicating LED. This is achieved by enabling the appropriate bit in the Key to LED setup byte (see Section 7.14 on page 36), and setting the desired outputs levels or PWMs in setup addresses 9 to 15 (see B ection 7.12 on page 34).

4.8 Trigger Modes

4.8.1 Timed Trigger

In 11-key mode, The QT1110 can be configured to use the internal clock as a timed trigger. In this case, the QT1110 is configured with a cycle period, such that each acquisition cycle starts a specified length of time after the start of the previous cycle. If the cycle period is set to 0, each acquisition cycle starts as soon as the previous one has finished, resulting in the acquisition cycles running back-to-back in a "free run" mode.

The use of a timed trigger, and the cycle period to be used, is set in the Device Mode setup byte (see Section 7.4 on page 30).

4.8.2 Synchronized Trigger

In 11-key mode, if a time trigger is not enabled, the QT1110 operates in "synchronized" mode. In this mode, SNS10K is used as a SYNC pin to trigger key acquisition, rather than using the device internal clock. In this case the maximum number of keys is reduced to 10.

The SYNC pin can use one of two methods to trigger key measurements, selectable via bit 4 of the Device Mode setup byte (see Section 7.4 on page 30): Low Level and Rising Edge.

With the Low Level method the QT1110 operates in "free run" mode for as long as the SYNC pin is read as a logical 0. When the SYNC pin goes high, the current measurement cycle will be finished and no more key measurements will be taken until the SYNC pin goes low again. The low level trigger should be a minimum of 1 ms so that there is sufficient time for the device to detect the low level.

With the Rising Edge method all enabled keys are measured once when a rising edge is detected on the SYNC pin. This allows key measurements to be synchronized to an external event or condition.

For example, the SYNC pin can be used by the host to synchronize several devices to each other. This would ensure that only one of the devices outputs pulses at any given time and signals from one QT1110 do not interfere with the measurements from another.

Another use for synchronizing to the rising edge is to steady the signals when the device is running off a mains transformer with insufficient mains frequency filtering that is causing a 50 Hz or 60 Hz ripple on Vdd. If the mains voltage is scaled down with a simple voltage divider and connected to the SYNC pin, then the key measurement can be triggered by the rising edge detected at a positive going zero-crossing. Note that in this case, each key signal will be taken at the same point in the cycle, so Vdd will be the same at each measurement for a given key and the signals will be steadier.

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4.9 Guard Channel Option

The device has a guard channel option (available in all key modes), which allows one key to be configured as a guard channel to help prevent false detection (see Figure 4-9 on page 20). Guard channel keys should be more sensitive than the other keys (physically bigger or larger Cs), subject to burst length limitations (see Section 4.11.2 on page 21).

With guard channel enabled, the designated key is connected to a sensor pad which detects the presence of touch and overrides any output from the other keys using the chip AKS feature. The guard channel option is enabled by the Guard Key setup byte (see Section 7.5 on page 31).

With the guard channel not enabled, all the keys work normally.

Note: If a key is already "in detect" when the guard channel becomes active, that key will remain in detect and the guard key will not activate until the active key goes out of detect.

Figure 4-9. Guard Channel Example

4.10 Self-test Functions

4.10.1 Internal Hardware Tests

Internal hardware tests check for hardware failure in the device internal memory areas and data paths. Any failure detected in the function or contents of application ROM, RAM or registers causes the device to reset itself. The application code is scanned with a CRC check routine to confirm that the application data is all correct.

The RAM and registers are checked periodically (every 10 seconds) for dynamic and static failures.

4.10.2 Functional Checks

Functional checks confirm that the device is operating within expected parameters; any failure detected in these tests is notified to the system host. The device will continue to operate in the event that such functional failures are detected.

The functional tests are:

• Check that the channel-measurement signals are within the defined range.

• Confirm that data stored in the EEPROM is valid.

These tests are carried out as the particular functions are used. For example, the EEPROM is checked when the device attempts to load data from EEPROM, and the channel signals are checked when a measurement is carried out.

Note: If a particular channel is unused, the threshold of that channel should be set to 0 to prevent the incorrect reporting of the unused channel as being in an error state.

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4.11 Signal Processing

4.11.1 Detection Integrator

The device features a detection integration mechanism, which acts to confirm a detection in a robust fashion. A perkey counter is incremented each time the key has exceeded its threshold. When this counter reaches a preset limit the key is finally declared to be touched. For example, if the DI limit is set to 10, then a key signal must fall by more than the key threshold, and remain below that level for 10 acquisitions, before the key is declared to be touched. Similarly, the DI is applied to a key that is going out of detect: it must take 10 acquisitions where the signal has not exceeded its detect threshold before it is declared to leave touch.

4.11.2 Burst Length Limitations

The maximum burst length is 2048 pulses. The recommended design is to use a capacitor that gives a signal of <1000 pulses.

The number of pulses in the burst can be obtained by reading the key signal (that is, the number of pulses to complete measurement of the key signal) over the SPI interface (see Section 6.8 on page 27). Alternatively, a sc complete measurement of the key signal) over the SPI interface (see Section 6.8 on can be used to measure the entire burst, and then the burst length divided by the time for a single pulse.

Note that the keys are independent of each other. It is therefore possible, for example, to have a signal of 100 on one key and a signal of 1000 on another.

4.11.3 Adjacent Key Suppression Technology

The device includes the Atmel patented Adjacent Key Suppression (AKS) technology to allow the use of tightly spaced keys on a keypad with no loss of selectability by the user.

AKS is enabled or disabled for each key individually; only one key out of those enabled for AKS may be reported as touched at any one time. The first key touched dominates and stays in detect until it is released, even if another
stronger key is reported. Once it is released, the next strongest key is reported. If two keys are simultan detected, the strongest key is reported, allowing a user to slide a finger across multiple keys with only the dominant key reporting touch.

Each key can be enabled for AKS processing via the AKS mask (see Section 7.11 on page 34). Keys outside the group of enabled keys may be in detect simultaneously.

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5. Control Commands

5.1 Introduction

The QT1110 control commands are those commands that affect the device operation.

The control commands are listed in Table 5-1 and are described individually in the following sections.

Note: Commands are implemented immediately upon reception, so a suitable delay is required for the operation to be completed before communications can be re-established.

5.2 Send Setups (0x01)

This command initiates the upload of the full settings table to the QT1110 (see Section 7. on page 29).

When this command is received, the QT1110 stops key measurement and waits until 42 bytes of setup data have been received. Key acquisition will restart after all the setup data has been received.

If enabled, a CRC check byte is transmitted (both ways) after the 42 bytes to confirm that they have been received correctly.

If CRC checking is not enabled, it is recommended that the host request a dump of setup data from the QT1110, and confirms that the data correctly matches the data sent.

The host must wait for at least 150 µs for the operation to be completed before communications can be re-established.

5.3 Calibrate All (0x03)

This command initiates the recalibration of all sensor keys.

The host must wait for at least 150 µs for the operation to be completed before communications can be re-established.

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5.4 Reset (0x04)

The Reset command forces the QT1110 to reset. If the setups data is present in the EEPROM, the setups are loaded into the device. Otherwise default settings are applied.

The host must wait for at least 160 ms for the operation to be completed before communications can be re-established.

5.5 Sleep (0x05)

The Sleep command puts the device into sleep mode (see Section 4.3 on page 18).

The host must wait for at least 150 µs after a low signal is applied to the $\overline{\text{SS}}$ or CHANGE pin to wake the device before communications can be re-established.

5.6 Store to EEPROM (0x0A)

Stores the current RAM contents to the QT1110 internal EEPROM. When the device is reset, it will automatically reload these settings.

The host must wait for at least 200 ms for the operation to be completed before communications can be re-established.

5.7 Restore from EEPROM (0x0B)

Settings stored in EEPROM are automatically loaded into RAM when the device is reset. If desired, these settings can be re-loaded into RAM using the *Restore from EEPROM* command.

The host must wait for at least 150 ms for the operation to be completed before communications can be re-established.

5.8 Erase EEPROM (0x0C)

This command erases the settings stored in EEPROM and then resets the QT1110. This causes the QT1110 to revert to its default settings.

The host must wait for at least 50 ms for the operation to be completed before communications can be re-established.

5.9 Recover EEPROM (0x0D)

This command "undeletes" the setup data that was previously stored in the device EEPROM and has been erased using the "Erase EEPROM" command.

Note: If valid settings have not previously been stored in the device EEPROM, the QT1110 continues to operate under the default settings.

The host must wait for at least 50 ms for the operation to be completed before communications can be re-established.

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5.10 Calibrate Key (0x1*k***)**

This command recalibrates the key specified by *k*. For example, to calibrate key 4, the host sends 0x14; to calibrate key 10, the host sends 0x1A.

The host must wait for at least 150 µs for the operation to be completed before communications can be re-established.

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6. Report Requests

6.1 Introduction

The host can request reports from the QT1110, as summarized in Table 6-1.

Note that SPI communications are full-duplex, so the host must transmit on the MOSI pin to keep the communications active, while reading data from the QT1110 on the MOSI pin. Failure to do this within 100 ms will cause the device to assume that the exchange has been abandoned and reset the SPI interface. The host should therefore send one or two "NULL" bytes, as appropriate, on the MOSI line as it receives the 1- or 2-byte report data from the device.

6.2 First Key (0xC0)

This command returns 1-byte report in the format shown in Table 6-2.

Table 6-2. Send First Key Report Format

DETECT: $0 = no \text{ key in detect; } 1 = \text{there is a key in detect.}$

NUMKEY: indicates the number of keys in detect:

0 = only one key is in detect (specified by "KEY_NUM")

 $1 =$ more than one key in detect.

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KEY_n: $0 = \text{key } n$ out of detect, $1 = \text{key } n$ in detect (where n is $0 - 10$).

6.4 Device Status (0xC2)

This command returns a 1-byte bit-field report indicating the overall status of the QT1110.

Table 6-4. Device Status Report Format

Bits 7 is always 1; the other bits are as follows:

DETECT: $0 = no$ key in detect, $1 = at$ least 1 key in detect.

CYCLE: 0 = cycle time is good, 1 = cycle time over-run. A cycle time over-run occurs when it takes longer to measure and process all the keys than the assigned cycle time.

ERROR: $0 = no$ key in error state, $1 = at$ least 1 key in error.

CHANGE: 0 = CHANGE pin is asserted, 1 = CHANGE pin is floating.

EEPROM: 0 = EEPROM is good, 1 = EEPROM has an error. If there are no settings stored in EEPROM, the EEPROM error bit is set and a zero EEPROM CRC is returned.

RESET: set to 1 after power-on or reset, cleared when "Device Status" is read.

GUARD: 0 = guard channel is not in detect, 1 = guard channel is active or in detect. This bit will be zero if the guard channel is not enabled.

6.5 EEPROM CRC (0xC3)

This command returns a 1-byte CRC checksum for the setup data in EEPROM.

6.6 RAM CRC (0xC4)

This command returns a 1-byte CRC checksum for the setup data in RAM.

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6.7 Error Keys (0xC5)

This command returns a 2-byte bit-field report indicating the error status of all 11 keys. Note that disabled keys do not report errors.

Table 6-5. Send All Keys Report Format

KEY_n: $0 = \text{key } n$ status good, $1 = \text{key } n$ in error (where n is $0-10$).

6.8 Signal for Key *k* **(0x2***k***)**

This command returns a 2-byte report containing the most recent measured signal for key *k*. The signal is returned as a 16-bit number, MSB first.

Table 6-6. Signal for Key *k* **Report Format**

6.9 Reference for Key *k* **(0x4***k***)**

This command returns a 2-byte report containing the reference signal for key *k*. The reference is returned as a 16-bit number, MSB first.

Table 6-7. Reference for Key *k* **Report Format**

6.10 Status for Key *k* **(0x8***k***)**

This command returns a 1-byte report containing the status for key *k*.

Table 6-8. Status for Key *k* **Report Format**

DETECT: 0ut of detect, 1 = in detect.

LBL: $0 =$ lower burst limit is good, $1 =$ lower burst limit has error.

MBL: 0 = maximum burst limit is good, 1 = maximum burst limit has error. The maximum burst limit is fixed at 2048 pulses.

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This command returns the previous 1-byte command that was received from the host. Note that this command does not return itself.

Table 6-10. Last Command

6.13 Setups (0xC8)

This command returns the 42 bytes of the setups table, starting with address 0, with the most significant bit first.

6.14 Device ID (0xC9)

This command returns 1 byte containing the device ID ($0x57$).

Table 6-11. Device ID Report Format

6.15 Firmware Version (0xCA)

Returns 1 byte containing the firmware version.

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7. Setups and Status Information

7.1 Introduction

The bytes of the setup table can be written to or read from individually. The setup table and the corresponding *Set*
and Ge*t* commands are listed in Table 7-1. Note that there is a discontinuity in the *Set* and Ge*t* c

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Table 7-1. Memory Map (Continued)

7.2 Setting Individual Settings

To set up an individual setup value, the host sends the command listed under the "Set Command" column in Table 7- 1, followed by a byte of data.

For details of the communication flow, see Section 4.1 on page 11.

7.3 Setting All the Setups

The host can send all 42 bytes of setup data to the QT1110 as a block using the Send Setups command. See Section 5.2 on page 22 for details.

7.4 Address 0: Device Mode

The Device Mode controls the overall operation of the device: number of keys, acquisition method, timing and trigger mechanism.

Table 7-2. Device Mode

KEY_AC: selects the trigger source to start key acquisition; 0 = SYNC pin, 1 = timed. **MODE:** selects 7-key or 11-key mode; 0 = default 7-key mode, 1 = 11-key mode. **SIGNAL:** selects serial or parallel acquisition of keys signals; 0 = serial, 1 = parallel.

SYNC: selects the trigger type when SYNC Pin is selected as the trigger to start key acquisition.

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SPI_EN: enables the Quick SPI interface; 0 = disable, 1 = enable.

See Section 4.1.6 on page 16 for details of the Quick SPI Mode report.

To exit this mode (and clear the *SPI_EN* bit), the command 0x36 should be sent. To save the settings to EEPROM and make Quick SPI mode active on startup, send the *Store to EEPROM* command (0x0A). Any other data sent is ignored in Quick SPI mode.

CHG: the CHANGE pin mode (see Section 4.5 on page 18):

0 = *Data* mode. In this mode the CHANGE pin is asserted to indicate unread data.

1 = *Touch* mode. In this mode the CHANGE pin is asserted when a key is being touched

or is in detect.

CRC: enables or disables CRC; 0 = disable, 1 = enable. When this option is enabled, each data exchange must have a CRC byte appended.

When report or setup data is being returned by the QT1110, a 1-byte checksum is returned. The host should confirm that this checksum is correct and, if not, should request the report again.

Where data is being sent by the host, a 1-byte CRC should be sent. The QT1110 returns the expected CRC byte in the same transaction the CRC byte is sent. In this way, the host can immediately determine whether the setup data bytes were received correctly.

Default GUARD_KEY value: 0 (Key 0) **Default GD_EN value:** 0 (disabled)
 Default CHG value: 0 (data mode) **Default CHG value:** 0 (data mode)
 Default CRC value: 0 (disabled) **Default CRC value:**

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7.6 Address 2: Detect Integrator Limit (DIL)/Drift Hold Time (DHT)

Table 7-4. Detect Integrator/Drift Hold Time

DIL: the detection integrator (DI) limit. To suppress false detections caused by spurious events like electrical noise, the device incorporates a DI counter mechanism. A per-key counter is incremented each time the channel has exceeded its threshold and stayed there for a number of acquisitions in succession, without going below the threshold level. When this counter reaches a preset limit the channel is finally declared to be touched. If on any acquisition the delta is not seen to exceed the threshold level, the counter is cleared and the process has to start from the beginning.

Note: A setting of 0 for DI is invalid; the valid range is 1 to 15.

DHT: the drift hold time. After a key-touch has been removed, the QT1110 pauses in the implementation of its "Drift" compensation for a time. After this time has expired, drift compensation continues as normal. The Drift Hold Time is a multiple of 160 ms, providing options from 0 to 2400 ms.

7.7 Address 3: Positive Threshold (PTHR)/Positive Hysteresis (PHYST)

Table 7-5. Positive Threshold (THR)/Positive Hystereis (HYST)

PTHR: the positive threshold for the signal. If a key signal is significantly higher than the reference signal, this typically indicates that the calibration data is no longer valid. In other words, some factor has changed since the calibration was carried out, thus rendering it invalid. Generally this is compensated for by the drift, but the greater the difference the longer this will take. In order to speed up this correction, the positive threshold is used: if the positive threshold is exceeded, the QT1110 (that is, all keys) is recalibrated.

PHYST: positive hysteresis. This setting provides a greater degree of control over the implementation of the positive threshold recalibration. The positive hysteresis operates as a "modifier" for the positive threshold. When a key signal is detected as being over the positive threshold, the positive threshold is reduced by a factor corresponding to the positive hysteresis so that the key will not go in and out of positive detection when the signal is on the borderline between drift-compensation of a positive error or recalibration.

The settings for positive hysteresis are:

- 00 = No change to positive threshold
- 01 = 12.5% reduction in positive-detect threshold
- 10 = 25% reduction in positive-detect threshold

11 = 37.5% reduction in positive-detect threshold

Default PTHR value: 4 (4 counts above reference) **Default PHYST value:** 2 (25% positive hysteresis)

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7.8 Address 4: Positive Drift Compensation (PDRIFT)

Table 7-6. Positive Drift Compensation

When changing ambient conditions cause a change in the key signal, the QT1110 will compensate through its drift functions. *Positive Drift* refers to the case where the signal for a key is greater than the reference.

Drift compensation occurs at a rate of 1 count per drift compensation period.

PDRIFT: the drift compensation period, in multiples of 160 ms. The valid range is 0 to 127, where 0 disables positive drift compensation.

Note: Drift compensation timing is paused while Drift Hold is activated, and continued when Drift Hold has timed out.

Default value: 6 (960 ms)

7.9 Address 5: Positive Recalibration Delay (PRD)

Table 7-7. Positive Recalibration Delay

If a key signal is determined to be above the positive threshold, the QT1110 will wait for this delay and confirm that the error condition is still present before initiating a recalibration.

PRD: the positive recalibration delay, in multiples of 160 ms. **Note:** All keys are recalibrated in the case of a positive recalibration.

Default value: 6 (960 ms)

7.10 Address 6: Lower Burst Limit (LBL)

Table 7-8. Lower Burst Limit

Normal QTouch signals are in the range of 100 to 1000 counts for each key. The lower burst limit determines the minimum signal that is considered as a valid acquisition. If the count is lower than the lower burst limit, it is considered not to be valid and the key is set to an Error state.

Note: Where a key has a signal of less than the LBL, a detection is not reported on that key. **Default value:** 18

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7.11 Addresses 7 – 8: AKS Mask

AKS_*n* **(AKS Mask):** 0 = key *n* AKS disabled, 1 = key *n* AKS enabled (where *n* is 0*–*10).

These bits control which keys have AKS enabled (see Section 3. on page 9). A "1" means the corresponding key has AKS enabled; a 0 means that the corresponding key has AKS disabled.

Default AKS mask: 0x07 and 0xFF (all keys have AKS enabled)

7.12 Addresses 9 – 15: Detect0 – Detect6 PWM

Each of the 7 detect pins can be configured to output a PWM signal to indicate whether the key is touched (in detect) or not touched (out of detect).

The Detect outputs must be enabled by selecting 7-key mode in the "Device Mode" setting (see Section 7.4 on page 30), and the corresponding "Key to LED" bits must be set to enable the individual *Detect* outputs for each key (see Section 7.14 on page 36).

Table 7-10. Detect0 – Detect6 PWM

IN_DETECT*n***:** PWM to output when key *n* is "In Detect" (where *n* is 0*–*6).

OUT_DETECT*n***:** PWM to output when key *n* is "Out of Detect" (where *n* is 0–7). This PWM is also output if the
DETECT output is "disconnected" from the key (that is, "LED_*n*" in address 17 is set to 0), allowing the ho directly control the PWM output.

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The values for the "IN_DETECT*n*" and "OUT_DETECT*n"* nibbles are listed in Table 7-11.

Default IN_DETECT*n* **value:** 8 (100% PWM – on) **Default OUT_DETECTn value:**

7.13 Address 16: LED Detect Hold Time

Table 7-12. LED Detect Hold Time

When a key is touched, if the "Detect" outputs and "Key to LED" options are enabled (see Section 7.12 and Section 7.14), the corresponding "Detect" pin will output its "In-Detect" PWM signal.

After the key touch is removed, the "Detect" output can be held at the "In-Detect" PWM signal for a time before
returning to the "Out of Detect" PWM signal. This allows a reasonable length of time for an LED to be illumina **Default value:** 0 (0 ms)

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7.14 Address 17: LED Fade/Key to LED

Table 7-13. LED Fade/Key to LED

FADE: enables/disables fading for all LEDs. This is a global setting; either all LEDs fade, or none of them.

- $0 =$ disable (no fade).
- $1 =$ enable fading on and off.

LED_*n*: activates the LED output for the corresponding key output DETECT*n* (where *n* is 0*–*6).

- 1 = enables the "Detect" output to follow the status of the corresponding key.
- 0 = disable this function, in which case the "Detect" pin will always output its "Out of Detect" PWM (see Section 7.12

on page 34).

Default FADE value: 0 (disabled)
Default LED_n value: 1 (enabled) **Default LED_n value:**

7.15 Address 18: LED Latch

Table 7-14. LED Latch

LATCH_*n***:** enables/disables latching of the LED for the corresponding key output DETECT*n* (where *n* is 0*–*6). 1 = enables latching. When latching is enabled for a given LED, the LED toggles its state each time the key is touched.

 $0 =$ disables latching.

Note that bit 7 is reserved and should be set to zero.

Default LATCH_*n* **value:** 0x00 (latch disabled)

7.16 Addresses 19 – 29: Negative Threshold (NTHR) / Negative Hysteresis (NHYST)

Table 7-15. Negative Threshold / Negative Hysteresis

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Table 7-15. Negative Threshold / Negative Hysteresis (Continued)

KEY_*n***_NTHR:** the negative threshold for key *n* (where *n* is 0*–*10).

The negative threshold determines how much the signal must fall (compared to the reference) before a key is considered to be "In Detect". This level will generally need to be tuned individually for each key. To disable an individual key, set the threshold for that key to 0.

KEY_*n***_NHYST:** the negative hysteresis applied to key *n* detection threshold (where *n* is $0 - 10$).

Negative Hysteresis operates as a "modifier" for the negative threshold in order to provide a greater degree of control over the detection of a "Touch". When a key signal is first detected as being under the negative threshold, the threshold is reduced by a factor corresponding to the selected negative hysteresis. This means that the key will not go in and out of detection when the signal is on the borderline between drift-compensation or touch detection.

The settings for negative hysteresis are:

- 00 No change to negative threshold
- 01 12.5% reduction in negative threshold
- 10 25% reduction in negative threshold
- 11 37.5% reduction in negative threshold

Default KEY_n_NTHR value: 10 counts
Default KEY_n_NHYST value: 2 (25 percent) Default KEY_n_NHYST value:

7.17 Address 30: Extend Pulse Time

Table 7-16. Extend Pulse Time

HIGH_TIME: Number of µs to extend the high pulse time. LOW_TIME: Number of us to extend the low pulse time.

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7.18 Addresses 31 – 41: Negative Drift Compensation (NDRIFT) / Negative Recalibration Delay (NRD)

Table 7-17. Negative Drift Compensation / Negative Recalibration Delay

KEY_*n***_NDRIFT:** the negative drift compensation for key *n* (where *n* is 0*–*10).

When changing ambient conditions cause a change in the key signal, the QT1110 will compensate through its drift functions. "Negative Drift" refers to the case where the signal for a key is lower than the reference. Drift compensation occurs at a rate of 1 count per drift compensation period. The entered number is a multiple of 320 ms. Note that as a key touch, or an approaching touch, naturally causes a negative change in the signal, negative drift should be carried out at a much slower rate than positive drift. Otherwise, a slowly approaching finger will not cause a touch detection, as the falling signal could be compensated through the negative drift mechanism.

Note: Drift compensation timing is paused while Drift Hold is activated, and continues when Drift Hold has timed out.

KEY_*n***_NRD:** the negative recalibration delay for key *n* (where *n* is 0 *–* 10).

In order to avoid a situation where a key remains "stuck" in detect due to, for example, changing environmental conditions, the "Negative Recalibration Delay" sets an upper limit on how long a key can remain "touched". When this time is exceeded, the QT1110 (that is, all keys) is recalibrated, taking this key (and any others which are in detect) out of detection. This delay is set in a multiple of 2560 ms.

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8. Specifications

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8.1 Absolute Maximum Specifications

CAUTION: Stresses beyond those listed under Absolute Maximum Specifications may cause permanent damage
to the device. This is a stress rating only and functional operation of the device at these or other conditions beyond

8.2 Recommended Operating Conditions

8.3 DC Specifications

Vdd = $5.0V$, Cs = 4.7 nF, Rs = 1 M Ω , Ta = recommended range, unless otherwise noted

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8.4 Timing Specifications

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8.5 SPI Bus Specifications

8.5.1 General Specifications

8.5.2 Full SPI Mode

8.5.3 Quick SPI Mode

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8.6 External Reset

8.7 Internal Resonator

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8.8 Power Consumption

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8.9 Mechanical Dimensions

8.9.1 AT42QT1110-MZ – 32-pin 5 x 5 mm QFN

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8.9.2 AT42QT1110-AZ – 32-pin 7 x 7 mm TQFP

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8.10.2 AT42QT1110-AZ – 32-pin 7 x 7 mm TQFP

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8.11 Part Number

8.12 Moisture Sensitivity Level (MSL)

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Revision History

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d.4 endstop datasheet

D2FS **Ultra Subminiature Basic Switch**

Simple construction and high reliability for long time

- **Developed for a few number of operations during a long period of use such as door-detection to avoid sabotage on meters.**
- **Simple construction with a single-leaf movable spring realizes reasonable cost.**
- **Self-clinching, right-angled and left-angled PCB terminals are also available.**

RoHS Compliant

PARTIAL PROPERTY AND REAL PROPERTY NEW

Model Number Legend

-A1 : PCB terminals (Left-angled)

List of Models

Contact Form

Contact Specifications

Note: For more information on the minimum applicable load, refer to *Using Micro Loads*.

D2FS **Ultra Subminiature Basic Switch**

Ratings

Mote: The rating values apply under the following test conditions.
Ambient temperature: 20 ± 2°C
Ambient humidity: 65 ± 5%
Operating frequency: 20 operations/min **Rated voltage Resistive load**

6 VDC 0.1 A

Characteristics

Note: The data given above are initial values.
*1. The values are at Free Position and Total Travel Position values for pin plunger, and Total Travel Position value for lever.
* Close or open circuit of the contact is 1

2

D2FS **Ultra Subminiature Basic Switch**

Terminals (Unit: mm)

● **PCB Terminals (Right-angled)** ● **PCB Terminals (Left-angled)**

Dimensions (Unit: mm) **/ Operating Characteristics**

The following illustrations and drawings are for D2FS models with PCB terminals (straight). Self-clinching, and right-angled, left angled terminals are omitted from the
following drawings. Refer to the above for the termi

● **Pin Plunger Models** D2FS-F-N@

Note: 1. Unless otherwise specified, a tolerance of ±0.4 mm applies to all dimensions.
2. The operating characteristics are for operation in the A direction (\downarrow).

3

Precautions

Refer to General Information.

- When using automatic soldering baths, we recommend solder-ing at 260°C within 5 seconds. Make sure that the liquid surface of the solder does not flow over the edge of the board. • When soldering terminals manually, perform soldering within 3
- seconds at iron tip temperature not higher than 350°C. Do not apply any external force for at least 1 minute after soldering. When applying solder, keep the solder away from the case of the Switch and do not allow solder or flux to flow into the case.

● **Side-actuated (Cam/Dog) Operation**

• When using a cam or dog to operate the Switch, factors such as the operating speed, operating frequency, push-button indentation, and material and shape of the cam or dog will affect the durability of the Switch. Confirm performance specifications under actual operating conditions before using the Switch in applications.

D2FS **Ultra Subminiature Basic Switch**

incorrect

• When handling the Switch, ensure that uneven pressure or, as shown in the following diagram, pressure in a direction other than the operating direction is not applied to the Actuator, otherwise the Actuator or Switch may be damaged, or durability may be decreased.

● **Using Micro Loads**

• Even when using micro load models within the operating range, inrush currents or surges may decrease the life expectancy of the Switch. Therefore, insert a contact protection circuit where necessary.

● **Application Environment**

• Do not use the Switch in locations that are subject to toxic gas, silicon, excessive dust, excessive dirt, high temperatures, high humidity, sudden temperature changes, water splashes, or oil splashes.

Otherwise, damage resulting by faulty contact of the Switch contacts, corrosion, or other causes, or other functional faults may occur.

Note: Do not use this document to operate the Unit. OMRON Corporation
Electronic and Mechanical Corporation Example 3 Electronical Components Company **Contact: www.omron.com/ecb**

Cat. No. B121-E1-04 0117(0207)(O)

4

d.5 operational amplifier datasheet

MCP601/1R/2/3/4 MICROCHIP

2.7V to 6.0V Single Supply CMOS Op Amps

Features

- Single-Supply: 2.7V to 6.0V
- Rail-to-Rail Output
- Input Range Includes Ground • Gain Bandwidth Product: 2.8 MHz (typical)
- Unity-Gain Stable
- Low Quiescent Current: 230 µA/amplifier (typical)
- Chip Select (CS): **MCP603 only**
- Temperature Ranges:
- Industrial: -40°C to +85°C
- Extended: -40° C to $+125^{\circ}$ C
- Available in Single, Dual, and Quad

Typical Applications

- Portable Equipment
- A/D Converter Driver
- Photo Diode Pre-amp
- Analog Filters
- Data Acquisition
- Notebooks and PDAs • Sensor Interface

Available Tools

- SPICE Macro Models
- FilterLab® Software
- Mindi™ Simulation Tool
- MAPS (Microchip Advanced Part Selector)
- Analog Demonstration and Evaluation Boards
- Application Notes

Description

The Microchip Technology Inc. MCP601/1R/2/3/4 family of low-power operational amplifiers (op amps) are offered in single (MCP601), single with Chip Select (CS) (MCP603), dual (MCP602), and quad (MCP604) configurations. These op amps utilize an advanced CMOS technology that provides low bias current, high-speed operation, high open-loop gain, and rail-to-rail output swing. This product offering operates with a
single supply voltage that can be as low as 2.7V, while
drawing 230 µA (typical) of quiescent current per
amplifier. In addition, the common mode input voltage range goes 0.3V below ground, making these amplifiers ideal for single-supply operation.

These devices are appropriate for low power, battery operated circuits due to the low quiescent current, for A/D convert driver amplifiers because of their wide bandwidth or for anti-aliasing filters by virtue of their low input bias current.

The MCP601, MCP602, and MCP603 are available in standard 8-lead PDIP, SOIC, and TSSOP packages. The MCP601 and MCP601R are also available in a standard 5-lead SOT-23 package, while the MCP603 is available in a standard 6-lead SOT-23 package. The MCP604 is offered in standard 14-lead PDIP, SOIC, and TSSOP packages.

The MCP601/1R/2/3/4 family is available in the Industrial and Extended temperature ranges and has a power supply range of 2.7V to 6.0V.

Package Types V_{IN} + 3 V_{IN} – $\mathsf{\underline{2}}$ v_{ss} $\mathsf{\overline{4}}$ $6V_{\text{OUT}}$ 8 NC
7 Y_{DD} NC <u>[1</u> 5 NC $V_{\text{INA}} + 3$ V_{INA} – 2 V_{DD} 4 $V_{\text{INC}}+$ v_{ss} 8 V_{OUTC} VINC– V_{OUTA} ¹ $V_{INB} + 5$ VIND– 14 ^Voutd
13 V_{IND}– V_{OUTB} 7 V_{INB} – 6 VINA+ VIND+ VINB– VOUTB 7 6 V_{INA} – 2 V_{SS} 4 V_{OUTA} $V_{\text{INA}} + \frac{1}{3}$ 8 V_{DD} $5V_{\sf INB}+$ **MCP601 PDIP, SOIC, TSSOP MCP604 PDIP, SOIC, TSSOP MCP602 PDIP, SOIC, TSSOP** V_{IN} + 3 $v_{\rm ss}$ 2 $4V_{IN}$ – $\rm v_{\rm out}$ iii $\rm v_{\rm on}$ $\frac{1}{5}$ V_{DD} **MCP601 SOT23-5** V_{IN} + 3 $v_{\rm ss}$ 12 $4V_{IN}$ $\rm v_{out}$ iii $\rm v_{10}$ is $\rm v_{out}$ 6 V_{DI}
5 CS **MCP603 SOT23-6** V_{IN}– <u>12</u>
V_{IN}+ <u>13</u> V_{SS} $\overline{4}$ $6V_{\text{OUT}}$ 7 V_{DD} NC <u>[1</u> 8 CS 5 NC **MCP603 PDIP, SOIC, TSSOP** $\frac{1}{12}$ V_{IND} 11 10 9 V_{IN} + 3 $\rm v_{DD}$ 2 $4V_{IN}$ – V_{OUT} $\underline{\uparrow}$ \vee $\underline{\uparrow}$ V_{SS} $5V_{SS}$ **MCP601R SOT23-5**

1.0 ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings †

DC CHARACTERISTICS

 \dagger Motice: Stresses above those listed under "Absoluter"
Maximum Ratings" may cause permanent damage to the
device. This is a stress rating only and functional operation of
the device at those or any other conditions ab

Note 1: These specifications are not tested in either the SOT-23 or TSSOP packages with date codes older than YYWW = 0408.
In these cases, the minimum and maximum values are by design and characterization only.
2: All p

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AC CHARACTERISTICS

MCP603 CHIP SELECT (CS) CHARACTERISTICS

Timing Diagram.

TEMPERATURE CHARACTERISTICS

Thermal Resistance, 14L-TSSOP $\begin{array}{|c|c|c|c|c|}\n\hline\n0_1 & - & 100 & - & 0\n\end{array}$
 Note: The Industrial temperature parts operate over this extended range, but with reduced performance. The

Extended temperature specs do not

1.1 Test Circuits

The test circuits used for the DC and AC tests are
shown in Figure 1-2 and Figure 1-2. The bypass
capacitors are laid out according to the rules discussed
in **Section 4.5 "Supply Bypass"**.

Most Non-Inverting Gain Conditions.

Most Inverting Gain Conditions.

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2.0 TYPICAL PERFORMANCE CURVES

Note: Unless otherwise indicated, T_A = +25°C, V_{DD} = +2.7V to +5.5V, V_{SS} = GND, V_{CM} = V_{DD}/2, V_{OUT} ≈ V_{DD}/2,
V_L = V_{DD}/2, R_L = 100 kΩ to V_L, C_L = 50 pF and CS is tied low. **Note:** The graphs and tables provided following this note are a statistical summary based on a limited number of samples and are provided for informational purposes only. The performance characteristics listed herein are not tested or guaranteed. In some graphs or tables, the data presented may be outside the specified operating range (e.g., outside specified power supply range) and therefore outside the warranted range.

FIGURE 2-1: Open-Loop Gain, Phase vs. Frequency.

FIGURE 2-2: Slew Rate vs. Temperature.

Supply Voltage.

FIGURE 2-5: Quiescent Current vs. Temperature.

vs. Frequency.

Note: Unless otherwise indicated, T_A = +25°C, V_{DD} = +2.7V to +5.5V, V_{SS} = GND, V_{CM} = V_{DD}/2, V_{OUT} ≈ V_{DD}/2,
V_L = V_{DD}/2, R_L = 100 kΩ to V_L, C_L = 50 pF and CS is tied low.

FIGURE 2-7: Input Offset Voltage.

FIGURE 2-8: Input Offset Voltage vs. Temperature.

FIGURE 2-9: Input Offset Voltage vs.
Common Mode Input Voltage with V_{DD} = 2.7V.

FIGURE 2-10: Input Offset Voltage Drift.

FIGURE 2-11: CMRR, PSRR vs. Temperature.

FIGURE 2-12: Input Offset Voltage vs.
Common Mode Input Voltage with V_{DD} = 5.5V.

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Note: Unless otherwise indicated, T_A = +25°C<u>, V_{DD}</u> = +2.7V to +5.5V, V_{SS} = GND, V_{CM} = V_{DD}/2, V_{OUT} ≈ V_{DD}/2,
V_L = V_{DD}/2, R_L = 100 kΩ to V_L, C_L = 50 pF and CS is tied low.

Separation vs. Frequency.

1.E+02 1.E+03 1.E+04 1.E+05

100 1k 10k 100k

FIGURE 2-15: DC Open-Loop Gain vs. **Load Resistance (Ω)**

Load Resistance.

80

Note: Unless otherwise indicated, T_A = +25°C, V_{DD} = +2.7V to +5.5V, V_{SS} = GND, V_{CM} = V_{DD}/2, V_{OUT} ≈ V_{DD}/2,
V_L = V_{DD}/2, R_L = 100 kΩ to V_L, C_L = 50 pF and CS is tied low.

FIGURE 2-19: Gain Bandwidth Product,

Phase Margin vs. Load Resistance.

FIGURE 2-20: Output Voltage Headroom vs. Output Current.

Swing vs. Frequency.

FIGURE 2-22: DC Open-Loop Gain vs. Temperature.

FIGURE 2-23: Output Voltage Headroom vs. Temperature.

vs. Supply Voltage.

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Note: Unless otherwise indicated, T_A = +25°C<u>, V_{DD}</u> = +2.7V to +5.5V, V_{SS} = GND, V_{CM} = V_{DD}/2, V_{OUT} ≈ V_{DD}/2,
V_L = V_{DD}/2, R_L = 100 kΩ to V_L, C_L = 50 pF and CS is tied low.

FIGURE 2-25: Large Signal Non-Inverting Pulse Response.

FIGURE 2-26: Small Signal Non-Inverting Pulse Response.

FIGURE 2-28: Large Signal Inverting Pulse Response.

			$V_{DD} = 5.0V$				
		$G = -$					
	malayyay					ᅲ	
Output Voltage (20 mV/div)							
			Time (1 µs/div)				

FIGURE 2-29: Small Signal Inverting Pulse Response.

FIGURE 2-30: Quiescent Current Through V_{SS} vs. Chip Select Voltage (MCP603).

Note: Unless otherwise indicated, T_A = +25°C, V_{DD} = +2.7V to +5.5V, V_{SS} = GND, V_{CM} = V_{DD}/2, V_{OUT} ≈ V_{DD}/2,
V_L = V_{DD}/2, R_L = 100 kΩ to V_L, C_L = 50 pF and CS is tied low.

FIGURE 2-31: Chip Select Pin Input Current vs. Chip Select Voltage.

Internal Switch.

FIGURE 2-33: The MCP601/1R/2/3/4 family of op amps shows no phase reversal under input overdrive.

Input Voltage (below V_{SS}).

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3.0 PIN DESCRIPTIONS

Descriptions of the pins are listed in Table 3-1 (single op amps) and Table 3-2 (dual and quad op amps). **TABLE 3-1: PIN FUNCTION TABLE FOR SINGLE OP AMPS**

Note 1: The MCP601R is only available in the 5-pin SOT-23 package.

TABLE 3-2: PIN FUNCTION TABLE FOR DUAL AND QUAD OP AMPS

3.1 Analog Outputs

The op amp output pins are low-impedance voltage sources.

3.2 Analog Inputs

The op amp non-inverting and inverting inputs are high-impedance CMOS inputs with low bias currents.

3.3 Chip Select Digital Input

This is a CMOS, Schmitt-triggered input that places the part into a low power mode of operation.

3.4 Power Supply Pins

The positive power supply pin (V_{DD}) is 2.5V to 6.0V higher than the negative power supply pin (V_{SS}) . For normal operation, the other pins are at voltages between V_{SS} and V_{DD} .

Typically, these parts are used in a single (positive)
supply configuration. In this case, V_{SS} is connected to
ground and V_{DD} is connected to the supply. V_{DD} will
need bypass capacitors.

4.0 APPLICATIONS INFORMATION

The MCP601/1R/2/3/4 family of op amps are fabricated on Microchip's state-of-the-art CMOS process. They are unity-gain stable and suitable for a wide range of general purpose applications.

4.1 Inputs

4.1.1 PHASE REVERSAL

The MCP601/1R/2/3/4 op amp is designed to prevent phase reversal when the input pins exceed the supply
voltages. Figure 2-34 shows the input voltage exceeding the supply voltage without any phase reversal.

4.1.2 INPUT VOLTAGE AND CURRENT LIMITS

The ESD protection on the inputs can be depicted as shown in Figure 4-1. This structure was chosen to protect the input transistors, and to minimize input bias current (I_B). The input ESD diodes clamp the inputs when they try to go more than one diode drop below V_{SS}. They also clamp any voltages that go too far
above V_{DD}; their breakdown voltage is high enough to allow normal operation, and low enough to bypass quick ESD events within the specified limits.

Structures.

In order to prevent damage and/or improper operation of these op amps, the circuit they are in must limit the
currents and voltages at the V_{IN}+ and V_{IN}– pins (see
Absolute Maximum Ratings † at the beginning of Section 1.0 "Electrical Characteristics"). Figure 4-2
shows the recommended approach to protecting these inputs. The internal ESD diodes prevent the input pins
(V_{IN}+ and V_{IN}–) from going too far below ground, and
the resistors R₁ and R₂ limit the possible current drawn out of the input pins. Diodes D_1 and D_2 prevent the input pins (V_{IN}+ and V_{IN}–) from going too far above
V_{DD}, and dump any currents onto V_{DD}. When
implemented as shown, resistors R₁ and R₂ also limit the current through D_1 and D_2 .

It is also possible to connect the diodes to the left of resistors R_1 and R_2 . In this case, current through the diodes D_1 and D_2 needs to be limited by some other mechanism. The resistors then serve as in-rush current limiters; the DC current into the input pins $(V_{\rm IN}+$ and V_{IN}) should be very small.

A significant amount of current can flow out of the inputs when the common mode voltage (V_{CM}) is below
ground (V_{SS}); see Figure 2-34. Applications that are
high impedance may need to limit the useable voltage range.

4.1.3 NORMAL OPERATION

The Common Mode Input Voltage Range (V_{CMR})
includes ground in single-supply systems (V_{SS}), but
does not include V_{OD} . This means that the amplifier
input behaves linearly as long as the Common Mode
Innits ($V_{SS}-0.3V$

Figure 4-3 shows a unity gain buffer. Since V_{OUT} is the same voltage as the inverting input, V_{OUT} must be kept below V_{DD} –1.2V for correct operation.

Limited V_{OUT} Range.

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4.2 Rail-to-Rail Output

There are two specifications that describe the output swing capability of the MCP601/1R/2/3/4 family of op amps. The first specification (Maximum Output Voltage Swing) defines the absolute maximum swing that can be achieved under the specified load conditions. For instance, the output voltage swings to within 15 mV of the negative rail with a 25 kΩ load to $V_{DD}/2$. Figure 2-33 shows how the output voltage is limited when the input goes beyond the linear region of operation.

The second specification that describes the output swing capability of these amplifiers is the Linear Output
Voltage Swing. This specification defines the maximum
output swing that can be achieved while the amplifier is
still operating in its linear region. To verify linea operation in this range, the large signal (DC Open-Loop Gain (A_{OL})) is measured at points 100 mV inside the
supply rails. The measurement must exceed the specified gains in the specification table.

4.3 MCP603 Chip Select

The MCP603 is a single amplifier with Chip Select
(CS). When CS is pulled high, the supply current drops
to -0.7 µA (typ.), which is pulled through the CS pin to
V_{SS}. When this happens, the amp<u>lifie</u>r output is put into a high-impedance state. Pulling CS low enables the amplifier.

The CS pin has an internal 5 MΩ (typical) pull-down resistor connected to V_{SS}, so it will go low if the CS pin
is left floating. Figure 1-1 is the Chip Select timing diagram and shows the output voltage, supply currents,
and CS current in response to a CS pulse. Figure 2-27
shows the measured output voltage response to a CS pulse.

4.4 Capacitive Loads

Driving large capacitive loads can cause stability problems for voltage feedback op amps. As the load capacitance increases, the feedback loop's phase margin decreases and the closed-loop bandwidth is reduced. This produces gain peaking in the frequency response with overshoot and ringing in the step response.

When driving large capacitive loads with these operators and series
amps (e.g., > 40 pF when G = +1), a small series
resistor at the output (R_{iSO} in Figure 4-4) improves the
feedback loop's phase margin (stability) by m bandwidth will be generally lower than the bandwidth with no capacitive load.

MCP601/1R/2/3/4

Figure 4-5 gives recommended R_{ISO} values for different capacitive loads and gains. The x-axis is the
normalized load capacitance (C_L/G_N) in order to make it easier to interpret the plot for arbitrary gains. G_N is the circuit's noise gain. For non-inverting gains, G_N and the gain are equal. For inverting gains, $G_N = 1 + |Gain|$ (e.g., -1 V/V gives $G_N = +2$ V/V).

FIGURE 4-5: Recommended RISO values for capacitive loads.

Once you have selected R_{ISO} for your circuit, double-
check the resulting frequency response peaking and step response overshoot in your circuit. Evaluation on the bench and simulations with the MCP601/1R/2/3/4 SPICE macro model are very helpful. Modify R_{ISO}'s
value until the response is reasonable.

4.5 Supply Bypass

With this family of op amps, the power supply pin (V_{DD}) for single-supply) should have a local bypass capacitor (i.e., 0.01 µF to 0.1 µF) within 2 mm for good high-frequency performance. It also needs a bulk capacitor (i.e., 1 µF or larger) within 100 mm to provide large, slow currents. This bulk capacitor can be shared with nearby analog parts.

4.6 Unused Op Amps

An unused op amp in a quad package (MCP604)
should be configured as shown in Figure 4-6. These circuits prevent the output from toggling and causing crosstalk. Circuits A sets the op amp at its minimum noise gain. The resistor divider produces any desired reference voltage within the output voltage range of the op amp; the op amp buffers that reference voltage. Circuit B uses the minimum number of components and operates as a comparator, but it may draw more current.

4.7 PCB Surface Leakage

In applications where low input bias current is critical, printed circuit board (PCB) surface leakage effects need to be considered. Surface leakage is caused by humidity, dust or other contamination on the board. Under low humidity conditions, a typical resistance
between nearby traces is 10¹²Ω. A 5V difference would cause 5 pA of current to flow. This is greater than the MCP601/1R/2/3/4 family's bias current at +25°C (1 pA, typical).

The easiest way to reduce surface leakage is to use a guard ring around sensitive pins (or traces). The guard ring is biased at the same voltage as the sensitive pin. An example of this type of layout is shown in Figure 4-7.

1. Connect the guard ring to the inverting input pin (V_{IN}–) for non-inverting gain amplifiers, includ-
ing unity-gain buffers. This biases the guard ring to the common mode input voltage.

2. Connect the guard ring to the non-inverting input pin (V_{IN}+) for inverting gain amplifiers and
transimpedance amplifiers (converts current to voltage, such as photo detectors). This biases the guard ring to the same reference voltage as the op amp (e.g., $V_{DD}/2$ or ground).

4.8 Typical Applications

4.8.1 ANALOG FILTERS

Figure 4-8 and Figure 4-9 show low-pass, second-
order, Butterworth filters with a cutoff frequency of 10 Hz. The filter in Figure 4-8 has a non-inverting gain
of +1 V/V, and the filter in Figure 4-9 has an inverting gain of -1 V/V.

FIGURE 4-8: Second-Order, Low-Pass Sallen-Key Filter.

The MCP601/1R/2/3/4 family of op amps have low input bias current, which allows the designer to select larger resistor values and smaller capacitor values for these filters. This helps produce a compact PCB layout.
These filters, and others, can be designed using
Microchip's Design Aids; see **Section 5.2 "FilterLab®**
Software" and **Section 5.3 "Mindi™ Simulatior Tool"**.

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4.8.2 INSTRUMENTATION AMPLIFIER CIRCUITS

Instrumentation amplifiers have a differential input that subtracts one input voltage from another and rejects common mode signals. These amplifiers also provide a single-ended output voltage.

The three-op amp instrumentation amplifier is illustrated in Figure 4-10. One advantage of this approach is unity-
gain operation, while one disadvantage is that the common mode input range is reduced as R_2/R_G gets larger.

FIGURE 4-10: Three-Op Amp Instrumentation Amplifier.

The two-op amp instrumentation amplifier is shown in Figure 4-11. While its power consumption is lower than the three-op amp version, its main drawbacks are that the common mode range is reduced with higher gains and it must be configured in gains of two or higher.

FIGURE 4-11: Two-Op Amp Instrumentation Amplifier.

Both instrumentation amplifiers should use a bulk bypass capacitor of at least 1 µF. The CMRR of these amplifiers will be set by both the op amp CMRR and resistor matching.

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MCP601/1R/2/3/4

4.8.3 PHOTO DETECTION

The MCP601/1R/2/3/4 op amps can be used to easily convert the signal from a sensor that produces an output current (such as a photo diode) into a voltage (a transimpedance amplifier). This is implemented with a single resistor (R_2) in the feedback loop of the amplifiers shown in Figure 4-12 and Figure 4-13. The optional capacitor (C_2) sometimes provides stability for these circuits.

A photodiode configured in the Photovoltaic mode has zero voltage potential placed across it (Figure 4-12). In
this mode, the light sensitivity and linearity is
maximized, making it best suited for precision
applications. The key amplifier specifications for this
application common mode input voltage range (including ground), and rail-to-rail output.

FIGURE 4-12: Photovoltaic Mode Detector.

In contrast, a photodiode that is configured in the Photoconductive mode has a reverse bias voltage
across the photo-sensing element (Figure 4-13). This decreases the diode capacitance, which facilitates
high-speed operation (e.g., high-speed digital
communications). The design trade-off is increased
diode leakage current and linearity errors. The operam
needs to have a wi (GBWP).

FIGURE 4-13: Photoconductive Mode Detector.

5.0 DESIGN AIDS

Microchip provides the basic design tools needed for the MCP601/1R/2/3/4 family of op amps.

5.1 SPICE Macro Model

The latest SPICE macro model for the MCP601/1R/2/ 3/4 op amps is available on the Microchip web site at www.microchip.com. This model is intended to be an initial design tool that works well in the op amp's linear region of operation over the temperature range. See the model file for information on its capabilities.

Bench testing is a very important part of any design and cannot be replaced with simulations. Also, simulation results using this macro model need to be validated by comparing them to the data sheet specifications and characteristic curves.

5.2 FilterLab® Software

Microchip's FilterLab® software is an innovative software tool that simplifies analog active filter (using op amps) design. Available at no cost from the Microchip web site at www.microchip.com/filterlab, the FilterLab design tool provides full schematic diagrams of the filter circuit with component values. It also outputs the filter circuit in SPICE format, which can be used with the macro model to simulate actual filter performance.

5.3 Mindi™ Simulatior Tool

Microchip's Mindi™ simulator tool aids in the design of various circuits useful for active filter, amplifier and power-management applications. It is a free online simulation tool available from the Microchip web site at www.microchip.com/mindi. This interactive simulator enables designers to quickly generate circuit diagrams, simulate circuits. Circuits developed using the Mindi simulation tool can be downloaded to a personal computer or workstation.

5.4 MAPS (Microchip Advanced Part Selector)

MAPS is a software tool that helps semiconductor professionals efficiently identify Microchip devices that fit a particular design requirement. Available at no cost from the Microchip website at www.microchip.com/ maps, the MAPS is an overall selection tool for Microchip's product portfolio that includes Analog, Memory, MCUs and DSCs. Using this tool you can define a filter to sort features for a parametric search of devices and export side-by-side technical comparasion reports. Helpful links are also provided for Datasheets, Purchase, and Sampling of Microchip parts.

5.5 Analog Demonstration and Evaluation Boards

Microchip offers a broad spectrum of Analog Demonstration and Evaluation Boards that are designed to help you achieve faster time to market. For a complete listing of these boards and their corresponding user's guides and technical information, visit the Microchip web site at www.microchip.com/ analogtools.

Two of our boards that are especially useful are:

- **P/N SOIC8EV:** *8-Pin SOIC/MSOP/TSSOP/DIP Evaluation Board*
- **P/N SOIC14EV:** *14-Pin SOIC/TSSOP/DIP Evaluation Board*

5.6 Application Notes

The following Microchip Application Notes are avail-able on the Microchip web site at www.microchip. com/ appnotes and are recommended as supplemental reference resources.

ADN003: *"Select the Right Operational Amplifier for your Filtering Circuits",* DS21821

AN722: *"Operational Amplifier Topologies and DC Specifications",* DS00722

AN723: *"Operational Amplifier AC Specifications and Applications",* DS00723

AN884: *"Driving Capacitive Loads With Op Amps",* DS00884

AN990: *"Analog Sensor Conditioning Circuits – An Overview",* DS00990

These application notes and others are listed in the design guide:

"Signal Chain Design Guide", DS21825

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6.0 PACKAGING INFORMATION

6.1 Package Marking Information

Package Marking Information (Continued)

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5-Lead Plastic Small Outline Transistor (OT) ISOT-231

Notes

1. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.127 mm per side.
2. Dimensioning and tolerancing per ASME Y14.5M.
 BSC: Basic Dimension. Theoretically exact 0
;
 5 8 !-

Microchip Technology Drawing C04-091B

 $rac{0.28}{0.51}$

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6-Lead Plastic Small Outline Transistor (CH) ISOT-231

Notes:
1. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.127 mm per side. 0
;
 5 8 !-

2. Dimensioning and tolerancing per ASME Y14.5M.
BSC: Basic Dimension. Theoretically exact value shown without tolerances.

Microchip Technology Drawing C04-028B
8-Lead Plastic Dual In-Line (P) - 300 mil Body [PDIP]

Notes:

1. Pin 1 visual index feature may vary, but must be located with the hatched area.
2. § Significant Characteristic.
4. Dimensioning and tolerancing per ASME Y14.5M.
4. Dimensioning and tolerancing per ASME Y14.5M.
BSC: Bas

Microchip Technology Drawing C04-018B

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8-Lead Plastic Small Outline (SN) - Narrow, 3.90 mm Body [SOIC]

Notes:

2. § Significant Characteristic.

2. § Significant Characteristic.

3. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.15 mm per side.

4. Dimensioning a

 m β 5° - 15°

Mold Draft Angle Botto

Microchip Technology Drawing C04-057B

8-Lead Plastic Thin Shrink Small Outline (ST) - 4.4 mm Body [TSSOP]

Notes:

1. Pin 1 visual index feature may vary, but must be located within the hatched area.
2. Dimensions D and E1 do not include mold flash or proformations shall not exceed 0.15 mm per side.
BSC: Basic Dimension. Theoretically

Microchip Technology Drawing C04-086B

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14-Lead Plastic Dual In-Line (P) - 300 mil Body [PDIP]

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Rotes:

1. Pin1 visual index feature may vary, but must be located with the hatched area.

2. § Significant Characteristic.

4. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shal

Microchip Technolo Microchip Technology Drawing C04-005B

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 $.018$

14-Lead Plastic Small Outline (SL) - Narrow, 3.90 mm Body [SOIC]

Notes:
1. Pin 1 visual index feature may vary, but must be located within the hatched area.

2. § Significant Characteristic.
3. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.15 mm per side.
4. Dimensioning and tolerancing per ASME Y14.5M.
BSC: Basic Dim

Microchip Technology Drawing C04-065B

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14-Lead Plastic Thin Shrink Small Outline (ST) - 4.4 mm Body [TSSOP]

Notes:

1. Pin 1 visual index feature may vary, but must be located within the hatched area.
2. Dimensions D and E1 do not include mold flash or profusions. Mold flash or profusions shall not exceed 0.15 mm per side.
BSC: Basic Di

Microchip Technology Drawing C04-087B

NOTES:

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APPENDIX A: REVISION HISTORY

Revision G (December 2007)

- Updated Figure 2-15 and Figure 2-19.
- Updated Table 3-1 and Table 3-2. • Updated notes to **Section 1.0 "Electrical**
- **Characteristics"**.
- Expanded Analog Input Absolute Maximum Voltage Range (applies retroactively).
-
- Expanded operating V_{DD} to a maximum of 6.0V. • Added Figure 2-34.
- Added **Section 4.1.1 "Phase Reversal"**,
- **Section 4.1.2 "Input Voltage and Current Lim-its"**, and **Section 4.1.3 "Normal Operation"**.
- Corrected **Section 6.0 "Packaging Informa-tion"**.
-
- **Revision F (February 2004)** • Undocumented changes.
- **Revision E (September 2003)**
- Undocumented changes.
- **Revision D (April 2000)**

• Undocumented changes.

- **Revision C (July 1999)**
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- **Revision B (June 1999)**
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- **Revision A (March 1999)**
- Original Release of this Document.

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PRODUCT IDENTIFICATION SYSTEM

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